## IS42S16100H IS45S16100H



## 512K Words x 16 Bits x 2 Banks **16Mb SYNCHRONOUS DYNAMIC RAM**

#### **OCTOBER 2016**

## FEATURES

- Clock frequency: 200, 166, 143 MHz
- · Fully synchronous; all signals referenced to a positive clock edge
- Two banks can be operated simultaneously and independently
- Dual internal bank controlled by A11 (bank select)
- Single 3.3V power supply
- LVTTL interface
- Programmable burst length -(1, 2, 4, 8, full page)
- Programmable burst sequence: Sequential/Interleave
- 2048 refresh cycles every 32ms (Com, Ind, A1 grade) or 16ms (A2 grade)
- Random column address every clock cycle
- Programmable CAS latency (2, 3 clocks)
- · Burst read/write and burst read/single write operations capability
- · Burst termination by burst stop and precharge command
- Byte controlled by LDQM and UDQM
- · Packages: 400-mil 50-pin TSOP-II and 60-ball **TF-BGA**
- Temperature Grades: Commercial (0°C to +70°C) Industrial (-40°C to +85°C) Automotive A1 (-40°C to +85°C) Automotive A2 (-40°C to +105°C)

### DESCRIPTION

ISSI's 16Mb Synchronous DRAM IS42/4516100H is organized as a 524,288-word x 16-bit x 2-bank for improved performance. The synchronous DRAMs achieve high-speed data transfer using pipeline architecture. All inputs and outputs signals refer to the rising edge of the clock input.

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c.) potential liability of Integrated Silicon Solution, Inc is adequately protected under the circumstances

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a.) the risk of injury or damage has been minimized;

b.) the user assume all such risks; and



#### PIN CONFIGURATIONS 50-Pin TSOP (Type II)

		7
	1 50	
	2 49	DQ15
DQ1 🔳	3 48	3 🛄 DQ14
	4 47	
DQ2	5 46	) DQ13
DQ3 🔳	6 45	5 🔲 DQ12
	7 44	
DQ4 🔳	8 43	3 🛄 DQ11
DQ5 [	9 42	2 🔟 DQ10
	10 41	
DQ6 [	11 40	DQ9
DQ7	12 39	DQ8
	13 38	
LDQM [	14 37	
WE [	15 36	
	16 35	
RAS [	17 34	
cs 🗖	18 33	
A11 [	19 32	2 🔟 A9
A10 [	20 31	A8
A0 🔲	21 30	A7
A1 [	22 29	A6
A2 [[	23 28	3 🔟 A5
A3 [	24 27	7 🛄 A4
	25 26	GND GND
		<b>_</b>

## **PIN DESCRIPTIONS**

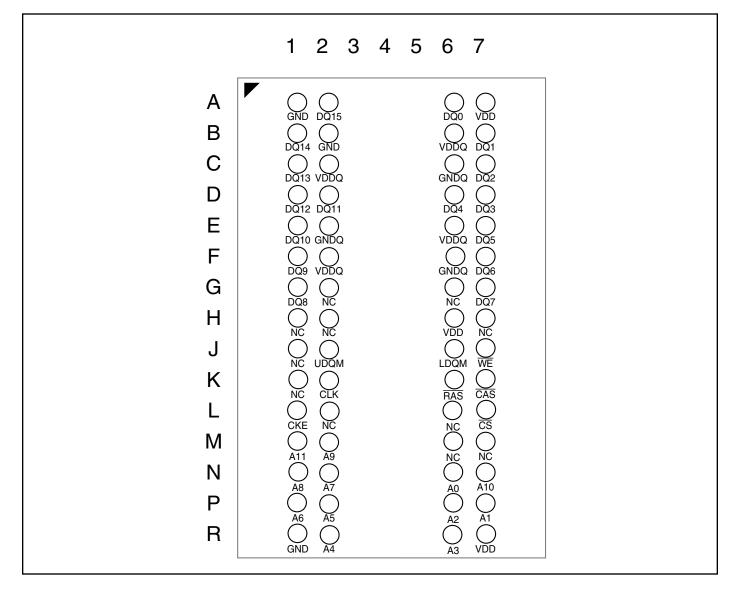
A0-A10	Row Address Input
A11	Bank Select Address
A0-A7	Column Address Input
DQ0 to DQ15	Data DQ
CLK	System Clock Input
CKE	Clock Enable
CS	Chip Select
RAS	Row Address Strobe Command

CAS	Column Address Strobe Command
WE	Write Enable
LDQM	Lower Bye, Input/Output Mask
UDQM	Upper Bye, Input/Output Mask
VDD	Power
GND	Ground
VDDQ	Power Supply for DQ Pin
GNDQ	Ground for DQ Pin
NC	No Connection



## **PIN CONFIGURATION**

PACKAGE CODE: B 60 BALL TF-BGA (Top View) (10.1 mm x 6.4 mm Body, 0.65 mm Ball Pitch)



#### **PIN DESCRIPTIONS**

A0-A10	Row Address Input
A0-A7	Column Address Input
A11	Bank Select Address
DQ0 to DQ15	Data I/O
CLK	System Clock Input
CKE	Clock Enable
CS	Chip Select
RAS	Row Address Strobe Command
CAS	Column Address Strobe Command

WE	Write Enable
LDQM, UDQM	x16 Input/Output Mask
Vdd	Power
GND	Ground
Vddq	Power Supply for I/O Pin
GNDQ	Ground for I/O Pin
NC	No Connection

## IS42S16100H, IS45S16100H

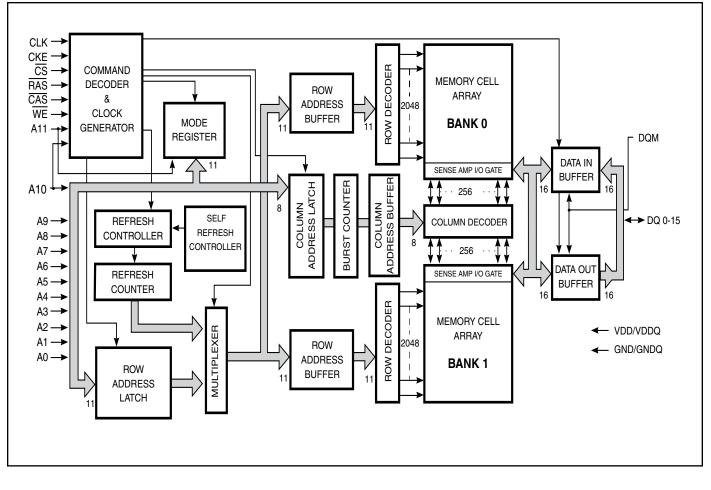


#### **PIN FUNCTIONS**

TSOP Pin No.	Symbol	Туре	Function (In Detail)
20 to 24 27 to 32	A0-A10	Input Pin	A0 to A10 are address inputs. A0-A10 are used as row address inputs during active command input and A0-A7 as column address inputs during read or write command input. A10 is also used to determine the precharge mode during other commands. If A10 is LOW during precharge command, the bank selected by A11 is precharged, but if A10 is HIGH, both banks will be precharged. When A10 is HIGH in read or write command cycle, the precharge starts automatically after the burst access. These signals become part of the OP CODE during mode register set command input.
19	A11	Input Pin	A11 is the bank selection signal. When A11 is LOW, bank 0 is selected and when high, bank 1 is selected. This signal becomes part of the OP CODE during mode register set command input.
16	CAS	Input Pin	$\overline{CAS}$ , in conjunction with the $\overline{RAS}$ and $\overline{WE}$ , forms the device command. See the "Command Truth Table" item for details on device commands.
34	CKE	Input Pin	The CKE input determines whether the CLK input is enabled within the device. When is CKE HIGH, the next rising edge of the CLK signal will be valid, and when LOW, invalid. When CKE is LOW, the device will be in either the power-down mode, the clock suspend mode, or the self refresh mode. The CKE is an asynchronous input.
35	CLK	Input Pin	CLK is the master clock input for this device. Except for CKE, all inputs to this device are acquired in synchronization with the rising edge of this pin.
18	CS	Input Pin	The $\overline{\text{CS}}$ input determines whether command input is enabled within the device. Command input is enabled when $\overline{\text{CS}}$ is LOW, and disabled with $\overline{\text{CS}}$ is HIGH. The device remains in the previous state when $\overline{\text{CS}}$ is HIGH.
2, 3, 5, 6, 8, 9, 11 12, 39, 40, 42, 43, 45, 46, 48, 49	DQ0 to DQ15	DQ Pin	DQ0 to DQ15 are DQ pins. DQ through these pins can be controlled in byte units using the LDQM and UDQM pins.
14, 36	LDQM, UDQM	Input Pin	LDQM and UDQM control the lower and upper bytes of the DQ buffers. In read mode, LDQM and UDQM control the output buffer. When LDQM or UDQM is LOW, the corresponding buffer byte is enabled, and when HIGH, disabled. The outputs go to the HIGH impedance state when LDQM/UDQM is HIGH. This function corresponds to $\overline{OE}$ in conventional DRAMs. In write mode, LDQM and UDQM control the input buffer. When LDQM or UDQM is LOW, the corresponding buffer byte is enabled, and data can be written to the device. When LDQM or UDQM is HIGH, input data is masked and cannot be written to the device.
17	RAS	Input Pin	$\overline{\text{RAS}}$ , in conjunction with $\overline{\text{CAS}}$ and $\overline{\text{WE}}$ , forms the device command. See the "Command Truth Table" item for details on device commands.
15	WE	Input Pin	$\overline{\text{WE}}$ , in conjunction with $\overline{\text{RAS}}$ and $\overline{\text{CAS}}$ , forms the device command. See the "Command Truth Table" item for details on device commands.
7, 13, 38, 44	VDDQ	Power Supply Pin	VDDQ is the output buffer power supply.
1, 25	VDD	Power Supply Pin	VDD is the device internal power supply.
4, 10, 41, 47	GNDQ	Power Supply Pin	GNDQ is the output buffer ground.
26, 50	GND	Power Supply Pin	GND is the device internal ground.



## FUNCTIONAL BLOCK DIAGRAM





#### ABSOLUTE MAXIMUM RATINGS<sup>(1)</sup>

Symbol	Parameters		Rating	Unit
VDD MAX	Maximum Supply Voltage	-	-1.0 to +4.6	V
VDDQ MAX	Maximum Supply Voltage for Output Buffer	-	–1.0 to +4.6	V
VIN	Input Voltage	-	–1.0 to +4.6	V
Vout	Output Voltage	-	–1.0 to +4.6	V
Pd max	Allowable Power Dissipation		1	W
lcs	Output Shorted Current		50	mA
Topr	Operating Temperature		0 to +70 -40 to +85 -40 to +85 -40 to +105	သံ သံ သံ
Тѕтс	Storage Temperature	-	–55 to +150	°C

## DC RECOMMENDED OPERATING CONDITION<sup>(2)</sup>

(At  $T_A = 0^{\circ}C$  to  $+70^{\circ}C$  for Commercial temperature,  $T_A = -40^{\circ}C$  to  $+85^{\circ}C$  for Industrial and A1 temperature,  $T_A = -40^{\circ}C$  to  $+105^{\circ}C$  for A2 temperature)

Symbol	Parameter	Min.	Тур.	Max.	Unit
Vdd, Vddq	Supply Voltage	3.0	3.3	3.6	V
Vін	Input High Voltage <sup>(3)</sup>	2.0	—	VDD + 0.3	V
VIL	Input Low Voltage <sup>(4)</sup>	-0.3		+0.8	V

#### **CAPACITANCE CHARACTERISTICS**<sup>(1,2)</sup> (At TA = 0 to +25°C, VDD = VDDQ = $3.3 \pm 0.3$ V, f = 1 MHz)

Symbol	Parameter	Тур.	Max.	Unit
CIN1	Input Capacitance: A0-A11		4	рF
CIN2	Input Capacitance: (CLK, CKE, CS, RAS, CAS, WE, LDQM, UDQM)	_	4	pF
CI/O	Data Input/Output Capacitance: DQ0-DQ15	_	5	рF

Notes:

1. Stress greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

2. All voltages are referenced to GND.

3. VIH (max) = V\_{DDQ} + 1.2V with a pulse width  $\leq$  3 ns.

4. VIL (min) = VDDQ - 1.2V with a pulse width  $\leq$  3 ns.



Symbol	Parameter	Test Condition			Speed	Min.	Max.	Unit
lı∟	Input Leakage Current	$0V \le V_{IN} \le VDD$ , with p the tested pin at $0V$	oins other than			-5	5	μA
Iol	Output Leakage Current	Output is disabled, 0V	$V \leq VOUT \leq VDD$			-5	5	μA
Vон	Output High Voltage Level	IOUT = -2 mA				2.4	_	V
Vol	Output Low Voltage Level	Ιουτ = +2 mA				_	0.4	V
Icc1	Operating Current <sup>(1,2)</sup>	One Bank Operation,	CAS latency =	3 Com.	-5	_	60	mA
		Burst Length=1		Com.	-6	_	55	
		trc $\geq$ trc (min.)		Com.	-7	_	50	
		IOUT = 0mA		Ind, A1	-6	_	60	
				A2	-6	—	65	
				Ind, A1	-7	—	55	
				A2	-7	—	60	
ICC2P	Precharge Standby Curren	tCKE≤Vil (max)	tск = 15ns	Com	—	—	3	mA
				Ind, A1	_			
ICC2PS	(In Power-Down Mode)		tcκ = ∞	Com	—	—		mA
				Ind, A1	—	—		
				A2	—			
Іссзи	Active Standby Current	СКЕ ≥ Vін (мім)	tск = 15ns		_	—	40	mA
ICC3NS	(In Non Power-Down Mode	e)	tc $\kappa = \infty$	Com	_	_	30	mA
				Ind, A1	_	_	30	
				A2	—		30	
ICC4	Operating Current	tск = tск (міл)	CAS latency =	3 Com	-5	_	80	mA
	(In Burst Mode) <sup>(1)</sup>	IOUT = 0mA	-	Com	-6	—	70	
				Ind, A1	-6	—	80	
				A2	-6	—	5 $55$ $5         -$	
				Com	-7	—		
				Ind, A1	-7	—		
				A2	-7	_		
			CAS latency =		-5	—		mA
				Com	-6	—		
				Ind, A1	-6	_		
				A2 Com	-6 -7			
				Ind, A1	-7 -7	_		
				A2	-7 -7	_		

#### DC ELECTRICAL CHARACTERISTICS (Recommended Operation Conditions unless otherwise noted.)

#### Notes:

1. These are the values at the minimum cycle time. Since the currents are transient, these values decrease as the cycle time increases. Also note that a bypass capacitor of at least 0.01 μF should be inserted between V<sub>DD</sub> and GND for each memory chip to suppress power supply voltage noise (voltage drops) due to these transient currents.

2. Icc1 and Icc4 depend on the output load. The maximum values for Icc1 and Icc4 are obtained with the output open state.



#### **DC ELECTRICAL CHARACTERISTICS** (Recommended Operation Conditions unless otherwise noted.)

Symbol	Parameter	<b>Test Condition</b>		Speed	Min.	Max.	Unit
Icc5	Auto-Refresh Current	trc = trc (міл)	$\overline{CAS}$ latency = 3 Com.	-5		50	mA
			Com.	-6	_	45	
			Ind, A1	-6	_	50	
			A2	-6		55	
			Com	-7		40	
			Ind, A1	-7		45	
		_	A2	-7		50	
			$\overline{CAS}$ latency = 2 Com	-5		50	mA
			Com	-6	_	45	
			Ind, A1	-6	_	50	
			A2	-6		55	
			Com	-7		40	
			Ind, A1	-7		45	
			A2	-7		50	
Icc <sub>6</sub>	Self-Refresh Current	$CKE \leq 0.2V$		_	_	2	mA

#### Notes:

1. These are the values at the minimum cycle time. Since the currents are transient, these values decrease as the cycle time increases. Also note that a bypass capacitor of at least 0.01 μF should be inserted between V<sub>DD</sub> and GND for each memory chip to suppress power supply voltage noise (voltage drops) due to these transient currents.

2. Icc1 and Icc4 depend on the output load. The maximum values for Icc1 and Icc4 are obtained with the output open state.



### AC CHARACTERISTICS<sup>(1,2,3)</sup>

tcsCommand Setup Time ( $\overline{CS}$ , $\overline{RAS}$ , $\overline{CAS}$ , $\overline{WE}$ , DQM)2-2-2tcHCommand Hold Time ( $\overline{CS}$ , $\overline{RAS}$ , $\overline{CAS}$ , $\overline{WE}$ , DQM)1-1-1tRcCommand Period (REF to REF / ACT to ACT)50-54-63tRasCommand Period (ACT to PRE)35100,00036100,00042tRPCommand Period (ACT to PRE)35100,00036100,00042tRpCommand Period (ACT to ACT)15-18-21tRcDActive Command To Read / Write Command Delay Time15-18-21tRcDCommand Period (ACT [0] to ACT[1])10-12-14tDPL3Input Data To Precharge Command Delay timeCAS Latency = 32CLK-2CLK-2CLKtDPL2 $\overline{CAS}$ Latency = 22CLK-2CLK + C2CLK + T2CLK + T2CLK + T2CLK + TtDAL3Input Data To Active / Refresh Command Delay time (During Auto-Precharge) $\overline{CAS}$ Latency = 32CLK + T2CLK + T2CLK + T2CLK + TtDAL2 $\overline{CAS}$ Latency = 22CLK + T2CLK + T2CLK + T2CLK + T2CLK + Ttransition Time0.31.20.31.20.31.20.3transition Time0.31.20.31.20.31.20.3transition Time0.31.20.31.20.31.20.3tr				-{	5	-	6	-7	,		
tx2   CAS Latency = 2   8    8    8     tx2   Access Time From CLK <sup>(4)</sup> CAS Latency = 3 CAS Latency = 2    5    5.5      tcH   CLK HIGH Level Width   2    2.5    2.5    2.5     tcL   CLK HOW Level Width   2    2.5    2.5    2.5     tcA3   Output Data Hold Time   CAS Latency = 3   2    2.5    2.5     tcA2   Output HIGH Impedance Time   0    5    5.5      tcA3   Output HIGH Impedance Time   CAS Latency = 3    5    6    1    1	mbol	Parameter		Min.	Max.	Min.	Max.	Min.	Max.	Units	
thc2   CAS   Latency = 2    6    6      tcH   CLK HIGH Level Width   2    2.5    2.5     tcL   CLK LOW Level Width   CAS   2    2.5    2.5     tcH2   Output Data Hold Time   CAS   2.5    2.5    2.5     tL2   Output LOW Impedance Time:   CAS   Latency = 3    5    5.5      th23   Output HIGH Impedance Time:   CAS   Latency = 3    5    6    6      th23   Output Data Setup Time   1    1    1		Clock Cycle Time			_		_		_	ns ns	
tcl. CLK LOW Level Width 2 - 2.5 - 2.5   tork3 Output Data Hold Time $\overline{CAS}$ Latency = 3 2 - 2.0 - 2.0   tz Output LOW Impedance Time 0 - 0 - 0 - 0   hv2 Output HIGH Impedance Times $\overline{CAS}$ Latency = 3 - 5 - 5.5 -   hv2 Output HIGH Impedance Times $\overline{CAS}$ Latency = 2 - 6 - 6 - 6 - 6 - 6 - 1 1 1 1 1 1 - 1 - 1 - 1 1 1 1 1 1 - 1		Access Time From CLK <sup>(4)</sup>		_					5.5 6	ns ns	
tork3 tork2 Output Data Hold Time $\overline{CAS}$ Latency = 3 $\overline{CAS}$ Latency = 2 2 - 2.0 $2.5$ - 2.5 <t< td=""><td>н</td><td>CLK HIGH Level Width</td><td></td><td>2</td><td>_</td><td>2.5</td><td>_</td><td>2.5</td><td>_</td><td>ns</td></t<>	н	CLK HIGH Level Width		2	_	2.5	_	2.5	_	ns	
torial   CAS   Latercy = 2   2.5   —   2.5   —   2.5     tiz   Output LOW Impedance Time (B)   CAS   Latercy = 3   —   5   —   5   —   0   —   0     hr23   Output HIGH Impedance Time (B)   CAS   Latercy = 3   —   5   —   5.5   —   1   —   1   —   1   —   1   —   1   —   1   —   1   —   1   …	Ľ	CLK LOW Level Width		2	_	2.5	_	2.5	_	ns	
Hr23 Hr22Output HIGH Impedance Time(s) $\overline{CAS}$ Latency = 3 CAS Latency = 2-5 5.5 6-tbsInput Data Setup Time2-2-2-2tbHInput Data Hold Time1-1-111tasAddress Setup Time2-2-222taHAddress Hold Time1-1-1111tcKsCKE Setup Time2-2-22222tcKHCKE Hold Time1-1-11		Output Data Hold Time							_	ns ns	
Hr22CAS Latency = 2-6-6-Input Data Setup Time2-2-2-2IDHInput Data Hold Time1-1-11LASAddress Setup Time2-2-2-2LAHAddress Hold Time1-1-1-11LKSCKE Setup Time2-2-2-22LKHCKE Hold Time1-1-1-111LKKCKE Hold Time1-1-11 <t< td=""><td>Z</td><td>Output LOW Impedance Time</td><td></td><td>0</td><td>_</td><td>0</td><td>_</td><td>0</td><td>_</td><td>ns</td></t<>	Z	Output LOW Impedance Time		0	_	0	_	0	_	ns	
DHInput Data Hold Time1-1-1tasAddress Setup Time2-2-2taHAddress Hold Time1-1-1tcxsCKE Setup Time2-2-2tcxHCKE Hold Time1-1-1tcxACKE to CLK Recovery Delay Time1CLK+3-1CLK+3-1CLK+3tcxACKE to CLK Recovery Delay Time1CLK+3-1CLK+3-1CLK+3tcxACKE to CLK Recovery Delay Time1-1-11tcxACKE to CLK Recovery Delay Time1-1-11tcxACKE to CLK Recovery Delay Time50-54-633100,00042tcxACommand Period (REF to REF / ACT to ACT)50-54-63100,000421-11 <td< td=""><td></td><td>Output HIGH Impedance Time(5)</td><td></td><td></td><td></td><td></td><td></td><td></td><td>5.5 6</td><td>ns ns</td></td<>		Output HIGH Impedance Time(5)							5.5 6	ns ns	
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tarAddress Hold Time1-1-1tcxsCKE Setup Time2-2-2tcxHCKE Hold Time1-1-1tcxACKE to CLK Recovery Delay Time1CLK+3-1CLK+3-1CLK+3tcsCommand Setup Time (CS, RAS, CAS, WE, DQM)2-2-2tcHCommand Hold Time (CS, RAS, CAS, WE, DQM)1-1-1trcCommand Period (REF to REF / ACT to ACT)50-54-63trassCommand Period (ACT to PRE)35100,00036100,00042trapCommand Period (ACT to PRE)35100,00036100,00042trapCommand Period (ACT to PRE)35100,00036100,00042trapCommand Period (ACT [0] to ACT]15-18-21traccActive Command To Read / Write Command Delay Time15-18-21traccCommand Period (ACT [0] to ACT[1])10-12-14topL2CAS Latency = 32CLK-2CLK-2CLKtbal3Input Data To Active / Refresh Command Delay timeCAS Latency = 32CLK + -2CLK + trap-2CLK + traptbal2CAS Latency = 22CLK + RP-2CLK + trap-2CLK + trap-2CLK + traptbal2CAS Latency = 2CLK + trap-2CLK + t	θH	Input Data Hold Time		1	_	1	_	1	_	ns	
tcxsCKE Setup Time2-2-2tcxHCKE Hold Time1-1-11tcxACKE to CLK Recovery Delay Time1CLK+3-1CLK+3-1CLK+3tcsCommand Setup Time ( $\overline{CS}$ , $\overline{RAS}$ , $\overline{CAS}$ , $\overline{WE}$ , DQM)2-2-2tcHCommand Hold Time ( $\overline{CS}$ , $\overline{RAS}$ , $\overline{CAS}$ , $\overline{WE}$ , DQM)1-1-1trcCommand Hold Time ( $\overline{CS}$ , $\overline{RAS}$ , $\overline{CAS}$ , $\overline{WE}$ , DQM)1-1-1trcCommand Period (REF to REF / ACT to ACT)50-54-63trasCommand Period (ACT to PRE)35100,00036100,00042tracCommand Period (ACT to ACT)15-18-21tracCommand Period (ACT [0] to ACT[1])10-12-14toPL3Input Data To Precharge Command Delay Time $\overline{CAS}$ Latency = 32CLK-2CLK-2CLKtoPL2 $\overline{CAS}$ Latency = 22CLK-2CLK-2CLK-2CLKtbaL3Input Data To Active / Refresh Command Delay time $\overline{CAS}$ Latency = 22CLK +trap-2CLK+trap-2CLK+traptbaL2 $\overline{CAS}$ Latency = 22CLK+trap-2CLK+trap-2CLK+trap-2CLK+traptbaL4Transition Time $0.3$ $1.2$ $0.3$ $1.2$ $0.3$ $1.2$ $0.3$ tbaL5Exi	S	Address Setup Time		2	_	2	_	2	_	ns	
tckhCKE Hold Time1-1-1tckaCKE to CLK Recovery Delay Time1CLK+3-1CLK+3-1CLK+3tcsCommand Setup Time ( $\overline{CS}$ , $\overline{RAS}$ , $\overline{CAS}$ , $\overline{WE}$ , DQM)2-2-2tcHCommand Hold Time ( $\overline{CS}$ , $\overline{RAS}$ , $\overline{CAS}$ , $\overline{WE}$ , DQM)1-1-1tRcCommand Period (REF to REF / ACT to ACT)50-54-63tRasCommand Period (ACT to PRE)35100,00036100,00042tRPCommand Period (PRE to ACT)15-18-21tRcbActive Command To Read / Write Command Delay Time15-18-21tRcbCommand Period (ACT [0] to ACT[1])10-12-14tDPL3Input Data To Precharge Command Delay time $\overline{CAS}$ Latency = 22CLK-2CLK-2CLKtDAL3Input Data To Active / Refresh Command Delay time (During Auto-Precharge) $\overline{CAS}$ Latency = 22CLK+trp-2CLK+trp-2CLK+trptDAL3Exit Self-Refresh to Active Time $\overline{55}$ - $60$ - $70$ <t< td=""><td>ιH</td><td>Address Hold Time</td><td></td><td>1</td><td>_</td><td>1</td><td>_</td><td>1</td><td>_</td><td>ns</td></t<>	ιH	Address Hold Time		1	_	1	_	1	_	ns	
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tchCommand Hold Time ( $\overline{CS}$ , $\overline{RAS}$ , $\overline{CAS}$ , $\overline{WE}$ , DQM)1-1-1-1trcCommand Period (REF to REF / ACT to ACT)50-54-63tracCommand Period (ACT to PRE)35100,00036100,00042trapCommand Period (PRE to ACT)15-18-21tracActive Command To Read / Write Command Delay Time15-18-21tracCommand Period (ACT [0] to ACT[1])10-12-14topL3Input Data To Precharge Command Delay timeCAS Latency = 32CLK-2CLK-2CLKtopL2CAS Latency = 22CLK-2CLK-2CLK+trp-2CLK+trptopL3Input Data To Active / Refresh Command Delay time (During Auto-Precharge)CAS Latency = 32CLK +trp-2CLK+trp-2CLK+trptopL4Exit Self-Refresh to Active Time55-60-7070tr< <th>transition Time0.31.20.31.20.31.20.31.20.3traffRefresh Cycle Time (2048) for temperature Ta <math>\leq 85^{\circ}</math>-32-32-32-</th>	transition Time0.31.20.31.20.31.20.31.20.3traffRefresh Cycle Time (2048) for temperature Ta $\leq 85^{\circ}$ -32-32-32-	KA	CKE to CLK Recovery Delay Time		1CLK+3	3 —	1CLK+3	_	1CLK+3	_	ns
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tRCDActive Command To Read / Write Command Delay Time $15  18  21$ tRRDCommand Period (ACT [0] to ACT[1]) $10  12  14$ tDPL3Input Data To Precharge Command Delay timeCAS Latency = 3 $2CLK  2CLK  2CLK -$ tDPL2CAS Latency = 2 $2CLK  2CLK  2CLK  2CLK -$ tDAL3Input Data To Active / Refresh Command Delay time (During Auto-Precharge) TDAL2CAS Latency = 3 $2CLK+tRP  2CLK+tRP  2CLK+tRP -$ tDAL2CAS Latency = 2 $2CLK+tRP  2CLK+tRP  2CLK+tRP  2CLK+tRP  2CLK+tRP -$ txsrExit Self-Refresh to Active Time $55  60  70$ $70$ trTransition Time $0.3 1.2$ $0.3 1.2$ $0.3$ $1.2$ $0.3$ tREFRefresh Cycle Time (2048) for temperature TA $\leq 85^{\circ}C$ $ 32  32  -$	AS	Command Period (ACT to PRE)		35	100,000	36	100,000	42	100,000	ns	
tRRDCommand Period (ACT [0] to ACT[1])10 $ 12$ $ 14$ tDPL3Input Data To Precharge Command Delay time $\overline{CAS}$ Latency = 3 $2CLK$ $ 2CLK$ $ 2CLK$ tDPL2 $\overline{CAS}$ Latency = 2 $2CLK$ $ 2CLK$ $ 2CLK$ $ 2CLK$ tDAL3Input Data To Active / Refresh Command Delay time (During Auto-Precharge) TDAL2 $\overline{CAS}$ Latency = 3 $2CLK+tRP$ $ 2CLK+tRP$ $ 2CLK+tRP$ tDAL2 $\overline{CAS}$ Latency = 2 $2CLK+tRP$ $ 2CLK+tRP$ $ 2CLK+tRP$ $ 2CLK+tRP$ tDAL2 $\overline{CAS}$ Latency = 2 $2CLK+tRP$ $ 2CLK+tRP$ $ 2CLK+tRP$ $ 2CLK+tRP$ tDAL2 $\overline{CAS}$ Latency = 2 $2CLK+tRP$ $ 2CLK+tRP$ $ 2CLK+tRP$ $ 2CLK+tRP$ tDAL2 $\overline{CAS}$ Latency = 2 $2CLK+tRP$ $ 2CLK+tRP$ $ 2CLK+tRP$ $ 2CLK+tRP$ tDAL2 $\overline{CAS}$ Latency = 2 $2CLK+tRP$ $ 2CLK+tRP$ $ 2CLK+tRP$ $ 2CLK+tRP$ transition Time $0.3$ $1.2$ $0.3$ $1.2$ $0.3$ $1.2$ $0.3$ $1.2$ $0.3$ tREFRefresh Cycle Time (2048) for temperature TA $\leq 85^{\circ}C$ $ 32$ $ 32$ $-$	₽	Command Period (PRE to ACT)		15	—	18	—	21	_	ns	
tDPL3Input Data To Precharge Command Delay time $\overline{CAS}$ Latency = 3 $2CLK$ $ 2CLK$ $ 2CLK$ tDPL2 $\overline{CAS}$ Latency = 2 $2CLK$ $ 2CLK$ $ 2CLK$ $ 2CLK$ tDAL3Input Data To Active / Refresh Command Delay time (During Auto-Precharge) $\overline{CAS}$ Latency = 3 $2CLK+tRP$ $ 2CLK+tRP$ $ 2CLK+tRP$ tDAL2 $\overline{CAS}$ Latency = 2 $2CLK+tRP$ $ 2CLK+tRP$ $ 2CLK+tRP$ $ 2CLK+tRP$ txsRExit Self-Refresh to Active Time $\overline{CAS}$ Latency = 2 $2CLK+tRP$ $ 2CLK+tRP$ $ 2CLK+tRP$ trTransition Time $0.3$ $1.2$ $0.3$ $1.2$ $0.3$ $1.2$ $0.3$ tREFRefresh Cycle Time (2048) for temperature TA $\leq 85^{\circ}C$ $ 32$ $ 32$ $-$	RCD	Active Command To Read / Write Command De	elay Time	15	_	18	_	21	_	ns	
Command Delay timetDPL2 $\overline{CAS}$ Latency = 2 $2CLK$ $ 2CLK$ $ 2CLK$ tDAL3Input Data To Active / Refresh Command Delay time (During Auto-Precharge) $\overline{CAS}$ Latency = 3 $2CLK+tRP$ $ 2CLK+tRP$ $-$ <td>RD</td> <td>Command Period (ACT [0] to ACT[1])</td> <td></td> <td>10</td> <td>_</td> <td>12</td> <td>_</td> <td>14</td> <td>_</td> <td>ns</td>	RD	Command Period (ACT [0] to ACT[1])		10	_	12	_	14	_	ns	
tDAL3Input Data To Active / Refresh Command Delay time (During Auto-Precharge) $\overrightarrow{CAS}$ Latency = 3 $2CLK+tRP$ — $2CLK+tRP$ = $2CLK+tRP$ = $2CLK+tRP$	opl3	Input Data To Precharge Command Delay time		2CLK	—	2CLK	—		—	ns	
tDAL2Command Delay time (During Auto-Precharge) CAS Latency = 2 $2CLK+tRP - 2CLK+tRP - 2CLK+tR$	PL2	-	CAS Latency = 2	2CLK	_	2CLK	—	2CLK	_	ns	
txsr Exit Self-Refresh to Active Time 55 $-$ 60 $-$ 70   tr Transition Time 0.3 1.2 0.3 1.2 0.3   treef Refresh Cycle Time (2048) for temperature TA $\leq$ 85°C $-$ 32 $-$ 32 $-$								2CLK+trp		ns	
tr   Transition Time   0.3   1.2   0.3   1.2   0.3     tREF   Refresh Cycle Time (2048) for temperature TA $\leq$ 85°C   -   32   -   32   -	DAL2		CAS Latency = 2		P —		P —		—	ns	
tref Refresh Cycle Time (2048) for temperature TA $\leq$ 85°C - 32 - 32 -	SR				—				—	ns	
				0.3		0.3		0.3	1.2	ns	
$B_{1} = B_{1} B_$	REF	Refresh Cycle Time (2048) for temperature TA <	≦ 85°C	_	32	_	32	_	32	ms	
tref Refresh Cycle Time (2048) for temperature TA > 85°C (A2 only) <sup>6</sup> — — — — — —	REF	Refresh Cycle Time (2048) for temperature TA >	→ 85°C (A2 only) <sup>6</sup>	_	_	_	_	_	16	ms	

Notes:

1. When power is first applied, memory operation should be started 100 µs after VDD and VDDQ reach their stipulated voltages. Also note that the power-on sequence must be executed before starting memory operation.

2. Measured with t $\tau$  = 1 ns. If clock rising time is longer than 1ns, (t $\tau$ /2 - 0.5)ns should be added to the parameter.

3. The reference level is 1.4 V when measuring input signal timing. Rise and fall times are measured between VIH (min.) and VIL (max.). 4. Access time is measured at 1.4V with the load shown in the figure below.

5. The time tHz (max.) is defined as the time required for the output voltage to transition by ± 200 mV from VoH (min.) or VoL (max.) when the output is in the high impedance state.

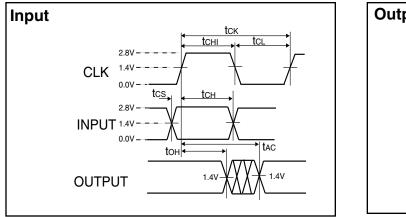
6. Self-Refresh Mode is not supported for A2 grade with TA > 85°C.

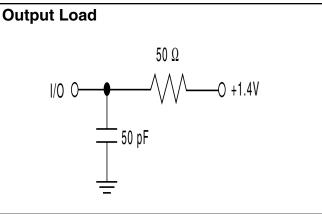


## **OPERATING FREQUENCY / LATENCY RELATIONSHIPS** (CAS Latency = 3)

SYMBOL	PARAMETER	-5	-6	-7	UNITS
_	Clock Cycle Time	5	6	7	ns
_	Operating Frequency	200	166	143	MHz
tcac	CAS Latency	3	3	3	cycle
trcd	Active Command To Read/Write Command Delay Time	3	3	3	cycle
trac	RAS Latency (tRcD + tCAC)	6	6	6	cycle
trc	Command Period (REF to REF / ACT to ACT)	10	9	9	cycle
tras	Command Period (ACT to PRE)	7	6	6	cycle
trp	Command Period (PRE to ACT)	3	3	3	cycle
trrd	Command Period (ACT[0] to ACT [1])	2	2	2	cycle
tccd	Column Command Delay Time (RE AD, READA, WRIT, WRITA)	1	1	1	cycle
tdpl.	Input Data To Precharge Command Delay Time	2	2	2	cycle
<b>t</b> dal	Input Data To Active/Refresh Command Delay Time (During Auto-Precharge)	5	5	5	cycle
trbd	Burst Stop Command To Output in HIGH-Z Delay Time (Read)	3	3	3	cycle
twвd	Burst Stop Command To Input in Invalid Delay Time (Write)	0	0	0	cycle
trql	Precharge Command To Output in HIGH-Z Delay Time (Read)	3	3	3	cycle
twd∟	Precharge Command To Input in Invalid Delay Time (Write)	0	0	0	cycle
tpql	Last Output To Auto-Precharge Start Time (Read)	-2	-2	-2	cycle
tqмd	DQM To Output Delay Time (Read)	2	2	2	cycle
tdмd	DQM To Input Delay Time (Write)	0	0	0	cycle
tмср	Mode Register Set To Command Delay Time	2	2	2	cycle

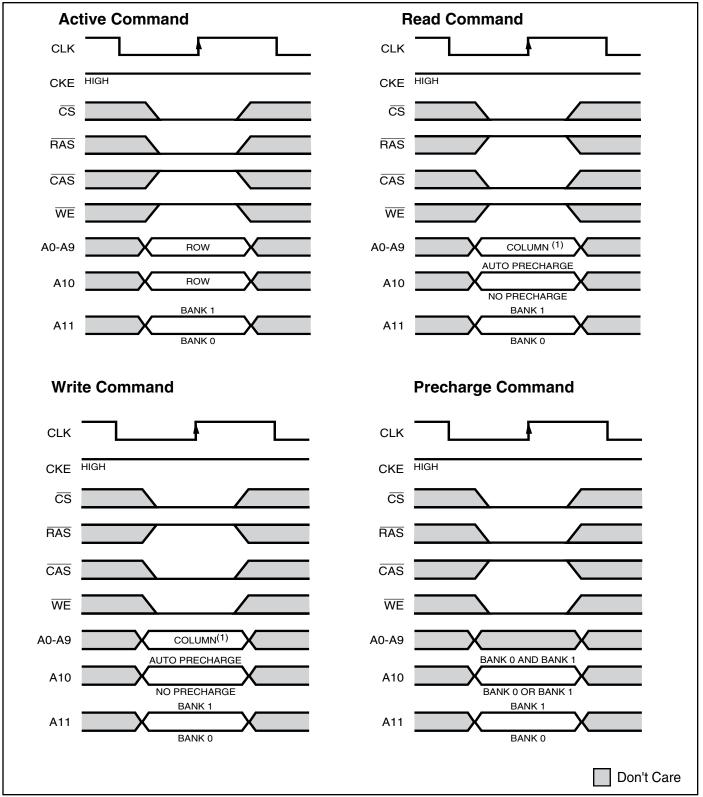
#### **ACTEST CONDITIONS** (Input/Output Reference Level: 1.4V)







### COMMANDS

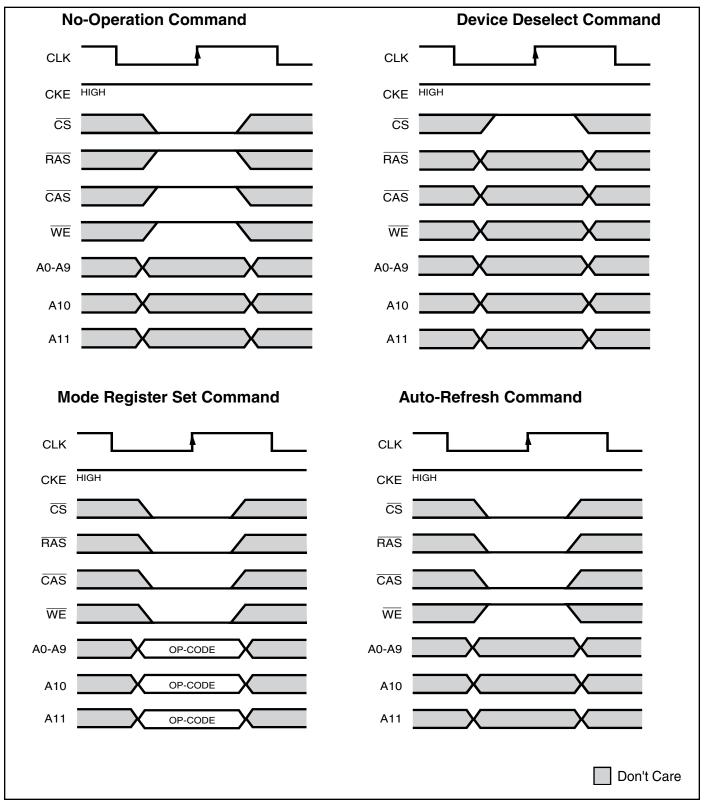


#### Notes:

1. A8-A9 = Don't Care.

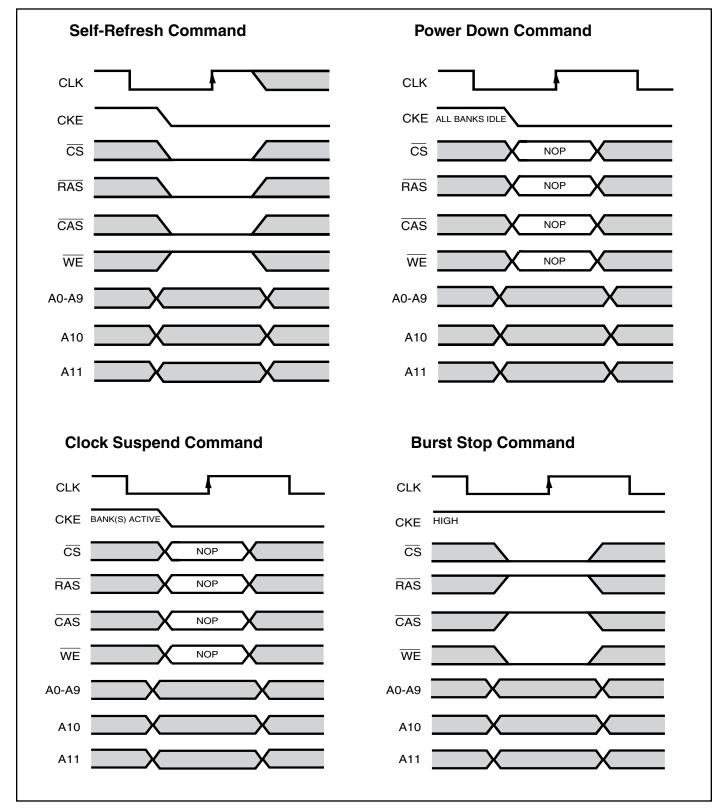


#### COMMANDS (cont.)





## COMMANDS (cont.)





#### Mode Register Set Command

#### $(\overline{CS}, \overline{RAS}, \overline{CAS}, \overline{WE} = LOW)$

The IS42/4516100H product incorporates a register that defines the device operating mode. This command functions as a data input pin that loads this register from the pins A0 to A11. When power is first applied, the stipulated power-on sequence should be executed and then the IS42/4516100H should be initialized by executing a mode register set command.

Note that the mode register set command can be executed only when both banks are in the idle state (i.e. deactivated).

Another command cannot be executed after a mode register set command until after the passage of the period tMCD, which is the period required for mode register set command execution.

#### **Active Command**

 $(\overline{CS}, \overline{RAS} = LOW, \overline{CAS}, \overline{WE} = HIGH)$ 

The IS42/4516100H includes two banks of 2048 rows each. This command selects one of the two banks according to the A11 pin and activates the row selected by the pins A0 to A10.

This command corresponds to the fall of the  $\overline{RAS}$  signal from HIGH to LOW in conventional DRAMs.

#### **Precharge Command**

 $(\overline{CS}, \overline{RAS}, \overline{WE} = LOW, \overline{CAS} = HIGH)$ 

This command starts precharging the bank selected by pins A10 and A11. When A10 is HIGH, both banks are precharged at the same time. When A10 is LOW, the bank selected by A11 is precharged. After executing this command, the next command for the selected bank(s) is executed after passage of the period tRP, which is the period required for bank precharging.

This command corresponds to the RAS signal from LOW to HIGH in conventional DRAMs

#### **Read Command**

 $(\overline{CS}, \overline{CAS} = LOW, \overline{RAS}, \overline{WE} = HIGH)$ 

This command selects the bank specified by the A11 pin and starts a burst read operation at the start address specified by pins A0 to A9. Data is output following CAS latency.

The selected bank must be activated before executing this command.

When the A10 pin is HIGH, this command functions as a read with auto-precharge command. After the burst read completes, the bank selected by pin A11 is precharged. When the A10 pin is LOW, the bank selected by the A11 pin remains in the activated state after the burst read completes.

#### Write Command

 $(\overline{CS}, \overline{CAS}, \overline{WE} = LOW, \overline{RAS} = HIGH)$ 

When burst write mode has been selected with the mode register set command, this command selects the bank specified by the A11 pin and starts a burst write operation at the start address specified by pins A0 to A9. This first data must be input to the DQ pins in the cycle in which this command.

The selected bank must be activated before executing this command.

When A10 pin is HIGH, this command functions as a write with auto-precharge command. After the burst write completes, the bank selected by pin A11 is precharged. When the A10 pin is low, the bank selected by the A11 pin remains in the activated state after the burst write completes.

After the input of the last burst write data, the application must wait for the write recovery period (tDPL, tDAL) to elapse according to  $\overline{CAS}$  latency.

#### **Auto-Refresh Command**

 $(\overline{CS}, \overline{RAS}, \overline{CAS} = LOW, \overline{WE}, CKE = HIGH)$ 

This command executes the auto-refresh operation. The row address and bank to be refreshed are automatically generated during this operation.

Both banks must be placed in the idle state before executing this command.

The stipulated period (tRC) is required for a single refresh operation, and no other commands can be executed during this period.

The device goes to the idle state after the internal refresh operation completes.

This command must be executed periodically according to tREF specification (AC Characteristics).

This command corresponds to CBR auto-refresh in conventional DRAMs.



#### Self-Refresh Command

 $(\overline{CS}, \overline{RAS}, \overline{CAS}, CKE = LOW, \overline{WE} = HIGH)$ 

This command executes the self-refresh operation. The row address to be refreshed, the bank, and the refresh interval are generated automatically internally during this operation. The self-refresh operation is started by dropping the CKE pin from HIGH to LOW. The self-refresh operation continues as long as the CKE pin remains LOW and there is no need for external control of any other pins. The self-refresh operation is terminated by raising the CKE pin from LOW to HIGH. The next command cannot be executed until the device internal recovery period (txsR) has elapsed. After the self-refresh, since it is impossible to determine the address of the last row to be refreshed, an auto-refresh should immediately be performed for all addresses (4096 cycles).

Both banks must be placed in the idle state before executing this command.

#### **Burst Stop Command**

 $(\overline{CS}, \overline{WE}, = LOW, \overline{RAS}, \overline{CAS} = HIGH)$ 

The command forcibly terminates burst read and write operations. When this command is executed during a burst read operation, data output stops after the CAS latency period has elapsed.

#### **No Operation**

 $(\overline{CS}, = LOW, \overline{RAS}, \overline{CAS}, \overline{WE} = HIGH)$ 

This command has no effect on the device.

#### **Device Deselect Command**

 $(\overline{CS} = HIGH)$ 

This command does not select the device for an object of operation. In other words, it performs no operation with respect to the device.

#### **Power-Down Command**

#### (CKE = LOW)

When both banks are in the idle (inactive) state, or when at least one of the banks is not in the idle (inactive) state, this command can be used to suppress device power dissipation by reducing device internal operations to the absolute minimum. Power-down mode is started by dropping the CKE pin from HIGH to LOW. Power-down mode continues as long as the CKE pin is held low. All pins other than the CKE pin are invalid and none of the other commands can be executed in this mode. The power-down operation is terminated by raising the CKE pin from LOW to HIGH. The next command cannot be executed until the recovery period (tckA) has elapsed.

Since this command differs from the self-refresh command described above in that the refresh operation is not performed automatically internally, the refresh operation must be performed within the refresh period (treef). Thus the maximum time that power-down mode can be held is just under the refresh cycle time.

#### **Clock Suspend**

(CKE = LOW)

This command can be used to stop the device internal clock temporarily during a read or write cycle. Clock suspend mode is started by dropping the CKE pin from HIGH to LOW. Clock suspend mode continues as long as the CKE pin is held LOW. All input pins other than the CKE pin are invalid and none of the other commands can be executed in this mode. Also note that the device internal state is maintained. Clock suspend mode is terminated by raising the CKE pin from LOW to HIGH, at which point device operation restarts. The next command cannot be executed until the recovery period (tckA) has elapsed.

Since this command differs from the self-refresh command described above in that the refresh operation is not performed automatically internally, the refresh operation must be performed within the refresh period (tREF). Thus the maximum time that clock suspend mode can be held is just under the refresh cycle time.



## COMMAND TRUTH TABLE<sup>(1,2)</sup>

		C	KE									
Symbol	Command	n-1	n	CS	RAS	CAS	WEI	DQM	A11	A10	A9-A0	l/On
MRS	Mode Register Set <sup>(3,4)</sup>	Н	Х	L	L	L	L	Х	(	OP CO	DE	Х
REF	Auto-Refresh <sup>(5)</sup>	Н	Н	L	L	L	Н	Х	Х	Х	Х	HIGH-Z
SREF	Self-Refresh <sup>(5,6)</sup>	Н	L	L	L	L	Н	Х	Х	Х	Х	HIGH-Z
PRE	Precharge Selected Bank	Н	Х	L	L	Н	L	Х	BS	L	Х	Х
PALL	Precharge Both Banks	Н	Х	L	L	Н	L	Х	Х	Н	Х	Х
ACT	Bank Activate <sup>(7)</sup>	Н	Х	L	L	Н	Н	Х	BS	Row	Row	Х
WRIT	Write	Н	Х	L	Н	L	L	Х	BS	L (	Column	18) X
WRITA	Write With Auto-Precharge <sup>(8)</sup>	Н	Х	L	Н	L	L	Х	BS	H (	Column	<sup>18)</sup> X
READ	Read <sup>(8)</sup>	Н	Х	L	Н	L	Н	Х	BS	L (	Column	18) X
READA	Read With Auto-Precharge <sup>(8)</sup>	Н	Х	L	Н	L	Н	Х	BS	Н	Column	(18) X
BST	Burst Stop <sup>(9)</sup>	Н	Х	L	Н	Н	L	Х	Х	Х	Х	Х
NOP	No Operation	Н	Х	L	Н	Н	Н	Х	Х	Х	Х	Х
DESL	Device Deselect	Н	Х	Н	Х	Х	Х	Х	Х	Х	Х	Х
SBY	Clock Suspend / Standby Mode	L	Х	Х	Х	Х	Х	Х	Х	Х	Х	Х
ENB	Data Write / Output Enable	Н	Х	Х	Х	Х	Х	L	Х	Х	Х	Active
MASK	Data Mask / Output Disable	Н	Х	Х	Х	Х	Х	Н	Х	Х	Х	HIGH-Z

#### DQM TRUTH TABLE<sup>(1,2)</sup>

		CK	(E	DQ	M
Symbol	Command	n-1	n	UPPER	LOWER
ENB	Data Write / Output Enable	Н	Х	L	L
MASK	Data Mask / Output Disable	Н	Х	Н	Н
ENBU	Upper Byte Data Write / Output Enable	Н	Х	L	Х
ENBL	Lower Byte Data Write / Output Enable	Н	Х	Х	L
MASKU	Upper Byte Data Mask / Output Disable	Н	Х	Н	Х
MASKL	Lower Byte Data Mask / Output Disable	Н	Х	Х	Н

#### CKE TRUTH TABLE<sup>(1,2)</sup>

		CKE									
Symbol	Command	Current State	n-1	n	$\overline{CS}$	RAS	CAS	WE	A11	A10	A9-A0
SPND	Start Clock Suspend Mode	Active	Н	L	Х	Х	Х	Х	Х	Х	Х
_	Clock Suspend	Other States	L	L	Х	Х	Х	Х	Х	Х	Х
_	Terminate Clock Suspend Mode	Clock Suspend	L	Н	Х	Х	Х	Х	Х	Х	Х
REF	Auto-Refresh	Idle	Н	Н	L	L	L	Н	Х	Х	Х
SELF	Start Self-Refresh Mode	Idle	Н	L	L	L	L	Н	Х	Х	Х
SELFX	Terminate Self-Refresh Mode	Self-Refresh	L	Н	L	Н	Н	Н	Х	Х	Х
			L	Н	Н	Х	Х	Х	Х	Х	Х
PDWN	Start Power-Down Mode	Idle	Н	L	L	Н	Н	Н	Х	Х	Х
			Н	L	Н	Х	Х	Х	Х	Х	Х
_	Terminate Power-Down Mode	Power-Down	L	Н	Х	Х	Х	Х	Х	Х	Х

#### **OPERATION COMMAND TABLE**<sup>(1,2)</sup>



urrent State	Command	Operation	$\overline{\text{CS}}$	RAS	CAS	WE	A11	A10	A9-A0
Idle	DESL	No Operation or Power-Down(12)	Н	Х	Х	Х	Х	Х	Х
	NOP	No Operation or Power-Down <sup>(12)</sup>	L	Н	Н	Н	Х	Х	Х
	BST	No Operation or Power-Down	L	Н	Н	L	Х	Х	Х
	READ / READA	Illegal	L	Н	L	Н	V	V	<b>V</b> (18)
	WRIT/WRITA	Illegal	L	Н	L	L	V	V	<b>V</b> <sup>(18)</sup>
	ACT	Row Active	L	L	Н	Н	V	V	<b>V</b> (18)
	PRE/PALL	No Operation	L	L	Н	L	V	V	Х
	REF/SELF	Auto-Refresh or Self-Refresh <sup>(13)</sup>	L	L	L	Н	Х	Х	Х
	MRS	Mode Register Set	L	L	L	L	0	P COI	DE
Row Active	DESL	No Operation	Н	Х	Х	Х	Х	Х	Х
	NOP	No Operation	L	Н	Н	Н	Х	Х	Х
	BST	No Operation	L	Н	Н	L	Х	Х	Х
	READ/READA	Read Start <sup>(17)</sup>	L	Н	L	Н	V	V	<b>V</b> (18)
	WRIT/WRITA	Write Start <sup>(17)</sup>	L	Н	L	L	V	V	<b>V</b> <sup>(18)</sup>
	ACT	Illegal <sup>(10)</sup>	L	L	Н	Н	V	V	<b>V</b> (18)
	PRE/PALL	Precharge <sup>(15)</sup>	L	L	Н	L	V	V	Х
	REF/SELF	Illegal	L	L	L	Н	Х	Х	Х
	MRS	Illegal	L	L	L	L	0	P COI	DE
Read	DESL	Burst Read Continues, Row Active When Done	Н	Х	Х	Х	Х	Х	Х
	NOP	Burst Read Continues, Row Active When Done	L	Н	Н	Н	Х	Х	Х
	BST	Burst Interrupted, Row Active After Interrupt	L	Н	Н	L	Х	Х	Х
	READ/READA	Burst Interrupted, Read Restart After Interrupt <sup>(16)</sup>	L	Н	L	Н	V	V	<b>V</b> (18)
	WRIT/WRITA	Burst Interrupted Write Start After Interrupt(11,16)	L	Н	L	L	V	V	V <sup>(18)</sup>
	ACT	Illegal <sup>(10)</sup>	L	L	Н	Н	V	V	<b>V</b> (18)
	PRE/PALL	Burst Read Interrupted, Precharge After Interrupt	L	L	Н	L	V	V	Х
	REF/SELF	Illegal	L	L	L	Н	Х	Х	Х
	MRS	Illegal	L	L	L	L	0	P COI	DE
Write	DESL	Burst Write Continues, Write Recovery When Done	Н	Х	Х	Х	Х	Х	Х
	NOP	Burst Write Continues, Write Recovery When Done	L	Н	Н	Н	Х	Х	Х
	BST	Burst Write Interrupted, Row Active After Interrupt	L	Н	Н	L	Х	Х	Х
	READ/READA	Burst Write Interrupted, Read Start After Interrupt <sup>(11,16)</sup>	L	Н	L	Н	V	V	V(18)
	WRIT/WRITA	Burst Write Interrupted, Write Restart After Interrupt(16)	L	Н	L	L	V	V	V <sup>(18)</sup>
	ACT	Illegal <sup>(10)</sup>	L	L	Н	Н	V	V	<b>V</b> (18)
	PRE/PALL	Burst Write Interrupted, Precharge After Interrupt	L	L	Н	L	V	V	Х
	REF/SELF	lllegal	L	L	L	Н	Х	Х	Х
	MRS	llegal	L	L	L	L		P COI	
Read With	DESL	Burst Read Continues, Precharge When Done	Н	Х	Х	Х	Х	Х	Х
Auto-	NOP	Burst Read Continues, Precharge When Done	L	Н	Н	Н	Х	Х	Х
Precharge	BST	Illegal	L	Н	Н	L	Х	Х	Х
-	READ/READA	llegal	L	Н	L	Н	V	V	<b>V</b> (18)
	WRIT/WRITA	llegal	L	Н	L	L	V	V	<b>V</b> (18)
	ACT	Illegal <sup>(10)</sup>	L	L	Н	Н	V	V	V <sup>(18)</sup>
	PRE/PALL	Illegal <sup>(10)</sup>	L	L	Н	L	V	V	Х
	REF/SELF	llegal	L	L	L	Н	Х	Х	Х
	MRS	lliegal	I.	T	T	T	0	P COI	



#### **OPERATION COMMAND TABLE**(1,2)

Current State	Command	Operation	CS	RAS	CAS	WE	A11	<u>A1</u>	A9-A0
Write With Auto-Precharge	DESL	Burst Write Continues, Write Recovery And Precharge When Done	Η	Х	Х	Х	Х	Х	Х
-	NOP	Burst Write Continues, Write Recovery And Precharge	L	Н	Н	Н	Х	Х	Х
	BST	Illegal	L	Н	Н	L	Х	Х	Х
	READ/READA	Illegal	L	Н	L	Н	V	V	V(18)
	WRIT/WRITA	Illegal	L	Н	L	L	V	۷	V(18)
	ACT	Illegal <sup>(10)</sup>	L	L	Н	Н	V	۷	V(18)
	PRE/PALL	Illegal <sup>(10)</sup>	L	L	Н	L	V	V	Х
	REF/SELF	Illegal	L	L	L	Н	Х	Х	Х
	MRS	Illegal	L	L	L	L	C	PCO	DE
Row Precharge	DESL	No Operation, Idle State After tRP Has Elapsed	Н	Х	Х	Х	Х	Х	Х
	NOP	No Operation, Idle State After tRP Has Elapsed	L	Н	Н	Н	Х	Х	Х
	BST	No Operation, Idle State After tre Has Elapsed	L	Н	Н	L	Х	Х	Х
	READ/READA	Illegal <sup>(10)</sup>	L	Н	L	Н	V	۷	V(18)
	WRIT/WRITA	Illegal <sup>(10)</sup>	L	Н	L	L	V	۷	V(18)
	ACT	Illegal <sup>(10)</sup>	L	L	Н	Н	V	۷	V(18)
	PRE/PALL	No Operation, Idle State After tre Has Elapsed <sup>(10)</sup>	L	L	Н	L	V	V	Х
	REF/SELF	Illegal	L	L	L	Н	Х	Х	Х
	MRS	Illegal	L	L	L	L	С	P CO	DE
Immediately	DESL	No Operation, Row Active After tRcD Has Elapsed	Н	Х	Х	Х	Х	Х	Х
Following	NOP	No Operation, Row Active After tRCD Has Elapsed	L	Н	Н	Н	Х	Х	Х
Row Active	BST	No Operation, Row Active After tRcD Has Elapsed	L	Н	Н	L	Х	Х	X
	READ/READA	lllegal <sup>(10)</sup>	L	Н	L	Н	V	V	V(18)
	WRIT/WRITA	Illegal <sup>(10)</sup>	L	Н	L	L	V	V	V(18)
	ACT	Illegal(10,14)	L	L	Н	Н	V	V	V(18)
	PRE/PALL	Illegal <sup>(10)</sup>	L	L	Н	L	V	V	Х
	REF/SELF	lllegal	L	L	L	Н	Х	Х	Х
	MRS	lllegal	L	L	L	L		P CC	
Write Recovery	DESL NOP	No Operation, Row Active After tDPL Has Elapsed No Operation, Row Active After tDPL Has Elapsed		X H	X H	X H	X X	X X	X X
	BST	No Operation, Row Active After tDPL Has Elapsed	L	Н	Н	L	Х	Х	Х
	READ/READA	Read Start	L	Н	L	Н	V	V	V(18)
	WRIT/WRITA	Write Restart	L	Н	L	L	V	V	V(18)
	ACT	Illegal <sup>(10)</sup>	L	L	Н	н	V	V	V(18)
	PRE/PALL	Illegal <sup>(10)</sup>	L	L	Н	L	V	۷	Х
	REF/SELF	lllegal	L	L	L	Н	Х	Х	Х
	MRS	lllegal	L	L	L	L	O	- CC	DE



#### **OPERATION COMMAND TABLE**(1,2)

Current State	Command	Operation	$\overline{\text{CS}}$	RAS	$\overline{CAS}$	$\overline{WE}$	A11	A10	A9-A0
Write Recovery	DESL	No Operation, Idle State After tDAL Has Elapsed	Н	Х	Х	Х	Х	Х	Х
With Auto-	NOP	No Operation, Idle State After tDAL Has Elapsed	L	Н	Н	Н	Х	Х	Х
Precharge	BST	No Operation, Idle State After tDAL Has Elapsed	L	Н	Н	L	Х	Х	Х
	READ/READA	Illegal <sup>(10)</sup>	L	Н	L	Н	V	V	<b>V</b> (18)
	WRIT/WRITA	Illegal <sup>(10)</sup>	L	Н	L	L	V	V	<b>V</b> (18)
	ACT	Illegal <sup>(10)</sup>	L	L	Н	Н	V	V	V <sup>(18)</sup>
	PRE/PALL	Illegal <sup>(10)</sup>	L	L	Н	L	V	V	Х
	REF/SELF	Illegal	L	L	L	Н	Х	Х	Х
	MRS	Illegal	L	L	L	L	0	P COI	DE
Refresh	DESL	No Operation, Idle State After tRP Has Elapsed	Н	Х	Х	Х	Х	Х	Х
	NOP	No Operation, Idle State After tRP Has Elapsed	L	Н	Н	Н	Х	Х	Х
	BST	No Operation, Idle State After tRP Has Elapsed	L	Н	Н	L	Х	Х	Х
	READ/READA	llegal	L	Н	L	Н	V	V	<b>V</b> (18)
	WRIT/WRITA	Illegal	L	Н	L	L	V	V	V(18)
	ACT	Illegal	L	L	Н	Н	V	V	V <sup>(18)</sup>
	PRE/PALL	Illegal	L	L	Н	L	V	V	Х
	REF/SELF	Illegal	L	L	L	Н	Х	Х	Х
	MRS	llegal	L	L	L	L	0	P COI	DE
Mode Register	DESL	No Operation, Idle State After tMCD Has Elapsed	Н	Х	Х	Х	Х	Х	Х
Set	NOP	No Operation, Idle State After tMcD Has Elapsed	L	Н	Н	Н	Х	Х	Х
	BST	No Operation, Idle State After tMcD Has Elapsed	L	Н	Н	L	Х	Х	Х
	READ/READA	Illegal	L	Н	L	Н	V	V	V <sup>(18)</sup>
	WRIT/WRITA	llegal	L	Н	L	L	V	V	<b>V</b> (18)
	ACT	llegal	L	L	Н	Н	V	V	<b>V</b> (18)
	PRE/PALL	llegal	L	L	Н	L	V	٧	Х
	REF/SELF	llegal	L	L	L	Н	Х	Х	Х
	MRS	llegal	L	L	L	L	0	P COI	DE

Notes:

1. H: HIGH level input, L: LOW level input, X: "Don't Care" input, V: Valid data input

2. All input signals are latched on the rising edge of the CLK signal.

3. Both banks must be placed in the inactive (idle) state in advance.

4. The state of the A0 to A11 pins is loaded into the mode register as an OP code.

5. The row address is generated automatically internally at this time. The DQ pin and the address pin data is ignored.

6. During a self-refresh operation, all pin data (states) other than CKE is ignored.

7. The selected bank must be placed in the inactive (idle) state in advance.

8. The selected bank must be placed in the active state in advance.

9. This command is valid only when the burst length set to full page.

10. This is possible depending on the state of the bank selected by the A11 pin.

11. Time to switch internal busses is required.

12. The DRAM can be switched to power-down mode by dropping the CKE pin LOW when both banks in the idle state. Input pins other than CKE are ignored at this time.

13. The DRAM can be switched to self-refresh mode by dropping the CKE pin LOW when both banks in the idle state. Input pins other than CKE are ignored at this time.

14. Possible if tRRD is satisfied.

15. Illegal if tRAS is not satisfied.

16. The conditions for burst interruption must be observed. Also note that the DRAM will enter the precharged state immediately after the burst operation completes if auto-precharge is selected.

17. Command input becomes possible after the period tRCD has elapsed. Also note that the DRAM will enter the precharged state immediately after the burst operation completes if auto-precharge is selected.

18. A8,A9 = don't care.



### CKE RELATED COMMAND TRUTH TABLE<sup>(1)</sup>

		CH	(E							
Current State	Operation	n-1	n	CS	RAS	CAS	WE	A11	A10	A9-A0
Self-Refresh	Undefined	Н	Х	Х	Х	Х	Х	Х	Х	Х
	Self-Refresh Recovery <sup>(2)</sup>	L	Н	Н	Х	Х	Х	Х	Х	Х
	Self-Refresh Recovery <sup>(2)</sup>	L	Н	L	Н	Н	Х	Х	Х	Х
	Illegal <sup>(2)</sup>	L	Н	L	Н	L	Х	Х	Х	Х
	Illegal <sup>(2)</sup>	L	Н	L	L	Х	Х	Х	Х	Х
	Self-Refresh	L	L	Х	Х	Х	Х	Х	Х	Х
Self-Refresh Recovery	Idle State After tRc Has Elapsed	Н	Н	Н	Х	Х	Х	Х	Х	Х
	Idle State After tRc Has Elapsed	Н	Н	L	Н	Н	Х	Х	Х	Х
	Illegal	Н	Н	L	Н	L	Х	Х	Х	Х
	Illegal	Н	Н	L	L	Х	Х	Х	Х	Х
	Power-Down on the Next Cycle	Н	L	Н	Х	Х	Х	Х	Х	Х
	Power-Down on the Next Cycle	Н	L	L	Н	Н	Х	Х	Х	Х
	Illegal	Н	L	L	Н	L	Х	Х	Х	Х
	Illegal	Н	L	L	L	Х	Х	Х	Х	Х
	Clock Suspend Termination on the Next Cycle (2)	L	Н	Х	Х	Х	Х	Х	Х	Х
	Clock Suspend	L	L	Х	Х	Х	Х	Х	Х	Х
Power-Down	Undefined	Н	Х	Х	Х	Х	Х	Х	Х	Х
	Power-Down Mode Termination, Idle After That Termination <sup>(2)</sup>	L	Η	Х	Х	Х	Х	Х	Х	Х
	Power-Down Mode	L	L	Х	Х	Х	Х	Х	Х	Х
Both Banks Idle	No Operation	Н	Н	Н	Х	Х	Х	Х	Х	Х
	See the Operation Command Table	Н	Н	L	Н	Х	Х	Х	Х	Х
	Bank Active Or Precharge	Н	Н	L	L	Н	Х	Х	Х	Х
	Auto-Refresh	Н	Н	L	L	L	Н	Х	Х	Х
	Mode Register Set	Н	Н	L	L	L	L	0	P COE	ЭE
	See the Operation Command Table	Н	L	Н	Х	Х	Х	Х	Х	Х
	See the Operation Command Table	Н	L	L	Н	Х	Х	Х	Х	Х
	See the Operation Command Table	Н	L	L	L	Н	Х	Х	Х	Х
	Self-Refresh <sup>(3)</sup>	Н	L	L	L	L	Н	Х	Х	Х
	See the Operation Command Table	Н	L	L	L	L	L	0	P COE	ЭE
	Power-Down Mode <sup>(3)</sup>	L	Х	Х	Х	Х	Х	Х	Х	Х
Other States	See the Operation Command Table	Н	Н	Х	Х	Х	Х	Х	Х	Х
	Clock Suspend on the Next Cycle <sup>(4)</sup>	Н	L	Х	Х	Х	Х	Х	Х	Х
	Clock Suspend Termination on the Next Cycle	L	Н	Х	Х	Х	Х	Х	Х	Х
	Clock Suspend Termination on the Next C	CvcleL	L	Х	Х	Х	х	Х	Х	Х

Notes:

1. H: HIGH level input, L: LOW level input, X: "Don't Care" input

2. The CLK pin and the other input are reactivated asynchronously by the transition of the CKE level from LOW to HIGH. The minimum setup time (tcka) required before all commands other than mode termination must be satisfied.

3. Both banks must be set to the inactive (idle) state in advance to switch to power-down mode or self-refresh mode.

4. The input must be command defined in the operation command table.



#### TWO BANKS OPERATION COMMAND TRUTH TABLE<sup>(1,2)</sup>

Operation	$\overline{CS}$	BAS		WF	Δ11	A10	A9-A0	BANK	Previo BANK 1	us State BANK 0	Next S	State
DESL	<u>н</u>	X	X	X	X	X	X	Any	Any	Any	Any	
NOP	L	H	H	H	X	X	X	Any	Any	Any	Any	
BST		H	H	L	X	X	X	R/W/A	I/A	A	I/A	
DOT	-	••	••	-	Λ	Λ	Λ		I/A		I/A	
								I/A	R/W/A	I/A	A	
								I/A	I.	I/A	I	
READ/READA	L	Н	L	Н	Н	Н	CA <sup>(3)</sup>	I/A	R/W/A	I/A	RP	
					Н	Н	CA <sup>(3)</sup>	R/W	A	A	RP	
					Н	L	CA <sup>(3)</sup>	I/A	R/W/A	I/A	R	
					Н	L	CA <sup>(3)</sup>	R/W	А	А	R	
					L	Н	CA <sup>(3)</sup>	R/W/A	I/A	RP	I/A	
					L	Н	CA <sup>(3)</sup>	А	R/W	RP	Α	
					L	L	CA <sup>(3)</sup>	R/W/A	I/A	R	I/A	
					L	L	CA <sup>(3)</sup>	Α	R/W	R	А	
WRIT/WRITA	L	Н	L	L	Н	Н	CA <sup>(3)</sup>	I/A	R/W/A	I/A	WP	
					Н	Н	CA <sup>(3)</sup>	R/W	Α	А	WP	
					Н	L	CA <sup>(3)</sup>	I/A	R/W/A	I/A	W	
					Н	L	CA <sup>(3)</sup>	R/W	А	А	W	
					L	Н	CA <sup>(3)</sup>	R/W/A	I/A	WP	I/A	
					L	Н	CA <sup>(3)</sup>	А	R/W	WP	Α	
					L	L	CA <sup>(3)</sup>	R/W/A	I/A	W	I/A	
					L	L	CA <sup>(3)</sup>	A	R/W	W	Α	
ACT	L	L	Н	Н	Н	RA	RA	Any	I	Any	А	
					L	RA	RA		Any	A	Any	
PRE/PALL	L	L	Н	L	Х	Н	Х	R/W/A/I		I	I	
					Х	Н	Х	I/A	R/W/A/I	I	I	
					Н	L	Х	I/A	R/W/A/I	I/A	I	
					Н	L	Х	R/W/A/I		R/W/A/I		
					L	L	Х	R/W/A/I		I	I/A	
					L	L	Х	I/A	R/W/A/I		R/W/A/I	
REF	L	L	L	Н	Х	Х	Х					
MRS	L	L	L	L	0	PCO	DE	I	I	I	I	

Notes:

1. H: HIGH level input, L: LOW level input, X: HIGH or LOW level input, RA: Row Address, CA: Column Address

2. The device state symbols are interpreted as follows:

I Idle (inactive state)

A Row Active State

R Read

W Write

RP Read With Auto-Precharge

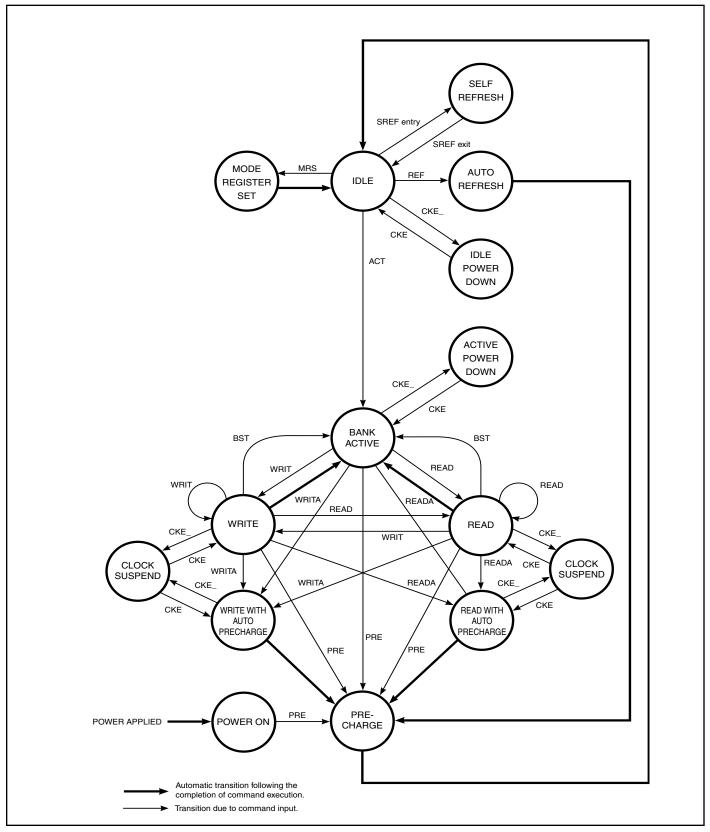
WP Write With Auto-Precharge

Any Any State

3. CA: A8,A9 = don't care.



## SIMPLIFIED STATE TRANSITION DIAGRAM (One Bank Operation)





#### **Device Initialization At Power-On**

(Power-On Sequence)

As is the case with conventional DRAMs, the DRAM product must be initialized by executing a stipulated power-on sequence after power is applied.

After power is applied and VDD and VDDQ reach their stipulated voltages, set and hold the CKE and DQM pins HIGH for 100  $\mu$ s. Then, execute the precharge command to precharge both bank. Next, execute the auto-refresh command twice or more and define the device operation mode by executing a mode register set command.

The mode register set command can be also set before auto-refresh command.

#### **Mode Register Settings**

The mode register set command sets the mode register. When this command is executed, pins A0 to A9, A10, and A11 function as data input pins for setting the register, and this data becomes the device internal OP code. This OP code has four fields as listed in the table below.

Input Pin	Field	
A11, A10, A9, A8, A7	Mode Options	
A6, A5, A4	CAS Latency	
A3	Burst Type	
A2, A1, A0	Burst Length	

Note that the mode register set command can be executed only when both banks are in the idle (inactive) state. If the Mode Register Set command is executed, the next command (except NOP or Deselect) cannot be executed until at least two clock cycles later, in order to avoid violating tMCD.

## **CAS** Latency

During a read operation, the between the execution of the read command and data output is stipulated as the  $\overline{CAS}$  latency. This period can be set using the mode register set command. The optimal  $\overline{CAS}$  latency is determined by the clock frequency and device speed grade. See the "Operating Frequency / Latency Relationships" item for details on the relationship between the clock frequency and the  $\overline{CAS}$  latency. See the table on the next page for details on setting the mode register.

## **Burst Length**

When writing or reading, data can be input or output data continuously. In these operations, an address is input only once and that address is taken as the starting address internally by the device. The device then automatically generates the following address. The burst length field in the mode register stipulates the number of data items input or output in sequence. In the DRAM product, a burst length of 1, 2, 4, 8, or full page can be specified. See the table on the next page for details on setting the mode register.

## **Burst Type**

The burst data order during a read or write operation is stipulated by the burst type, which can be set by the mode register set command. The DRAM product supports sequential mode and interleaved mode burst type settings. See the table on the next page for details on setting the mode register. See the "Burst Length and Column Address Sequence" item for details on DQ data orders in these modes.

#### Write Mode

Burst write or single write mode is selected by the OP code (A11, A10, A9) of the mode register.

A burst write operation is enabled by setting the OP code (A11, A10, A9) to (0,0,0). A burst write starts on the same cycle as a write command set. The write start address is specified by the column address and bank select address at the write command set cycle.

A single write operation is enabled by setting OP code (A11, A10, A9) to (0, 0, 1). In a single write operation, data is only written to the column address and bank select address specified by the write command set cycle without regard to the bust length setting.



## **MODE REGISTER**

	10 A9 A MODE	8 A7		<b>A5 A4</b> BT	A3 A2 A1 BL		Addre Mode					
							Ν	12	M1	MO	Sequential	Interleave
						Burst Ler	ngth	0	0	0	1	1
							-	0	0	1	2	2
								0	1	0	4	4
								0	1	1	8	8
					<u> </u>	-		1	0	0	Reserved	Reserve
								1	0	1	Reserved	Reserve
								1	1	0	Reserved	Reserve
								1	1	1	Full Page	Reserve
							Ν	//3		Туре	9	
						Burst Typ		0	S	equer		
				۰				1		terlea		
							N	/16	M5	M4	CAS Latency	
						Latency N			0	0	Reserved	
								0	0	1	Reserved	
								0	1	0	2	
								0	1	1	3	
								1	0	0	Reserved	
								1	0	1	Reserved	
								1	1	0	Reserved	
								1	1	1	Reserved	
M11	M10	M9	M8	M7	Write Mode							
0	0	1	0	0		& Single Writ						
0	0	0	0	0		& Burst Write						
U	U	0	0	U	Durst neau		,					

Note: Other values for these bits are reserved.



	Colun	nn A	ddress	Address \$	Sequence
Burst Length	A2	<b>A1</b>	A0	Sequential	Interleaved
2	Х	Х	0	0-1	0-1
	Х	Х	1	1-0	1-0
4	Х	0	0	0-1-2-3	0-1-2-3
	Х	0	1	1-2-3-0	1-0-3-2
	Х	1	0	2-3-0-1	2-3-0-1
	Х	1	1	3-0-1-2	3-2-1-0
8	0	0	0	0-1-2-3-4-5-6-7	0-1-2-3-4-5-6-7
	0	0	1	1-2-3-4-5-6-7-0	1-0-3-2-5-4-7-6
	0	1	0	2-3-4-5-6-7-0-1	2-3-0-1-6-7-4-5
	0	1	1	3-4-5-6-7-0-1-2	3-2-1-0-7-6-5-4
	1	0	0	4-5-6-7-0-1-2-3	4-5-6-7-0-1-2-3
	1	0	1	5-6-7-0-1-2-3-4	5-4-7-6-1-0-3-2
	1	1	0	6-7-0-1-2-3-4-5	6-7-4-5-2-3-0-1
	1	1	1	7-0-1-2-3-4-5-6	7-6-5-4-3-2-1-0
Full Page	n	n	n	Cn, Cn+1, Cn+2	None
(256)				Cn+3, Cn+4	
. ,				Cn-1(Cn+255),	
				Cn(Cn+256)	

#### **BURST LENGTH AND COLUMN ADDRESS SEQUENCE**

#### Notes:

1. The burst length in full page mode is 256.



#### BANK SELECT AND PRECHARGE ADDRESS ALLOCATION

Row	X0	—	Row Address
	X1	—	Row Address
	X2		Row Address
	X3		Row Address
	X4		Row Address
	X5		Row Address
	X6		Row Address
	X7	—	Row Address
	X8	—	Row Address
	X9	_	Row Address
	X10		Row Address (Active Command)
		0	Precharge of the Selected Bank (Precharge Command)
		1	Precharge of Both Banks (Precharge Command)
	X11	0	Bank 0 Selected (Precharge and Active Commands)
		1	Bank 1 Selected (Precharge and Active Commands)
Column	Y0	_	Column Address
	Y1		Column Address
	Y2		Column Address
	Y3		Column Address
	Y4		Column Address
	Y5		Column Address
	Y6		Column Address
	Y7		Column Address
	Y8		Don't Care
	Y9		Don't Care
	Y10	0	Auto-Precharge - Disabled
		1	Auto-Precharge - Enables
	Y11	0	Bank 0 Selected (Read and Write Commands)
		1	Bank 1 Selected (Read and Write Commands)



## **Burst Read**

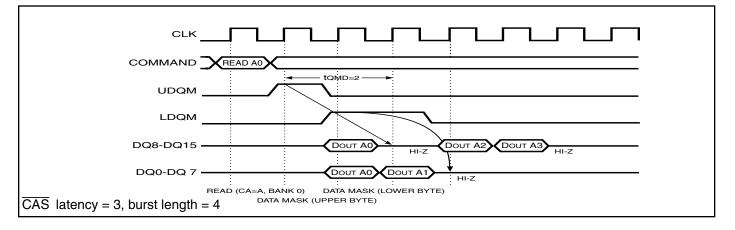
The read cycle is started by executing the read command. The address provided during read command execution is used as the starting address. First, the data corresponding to this address is output in synchronization with the clock signal after the CAS latency period. Next, data corresponding to an address generated automatically by the device is output in synchronization with the clock signal.

The output buffers go to the LOW impedance state CAS latency minus one cycle after the read command, and go to the HIGH impedance state automatically after the last data is output. However, the case where the burst length

is a full page is an exception. In this case the output buffers must be set to the high impedance state by executing a burst stop command.

Note that upper byte and lower byte output data can be masked independently under control of the signals applied to the U/LDQM pins. The delay period (tomb) is fixed at two, regardless of the CAS latency setting, when this function is used.

The selected bank must be set to the active state before executing this command.



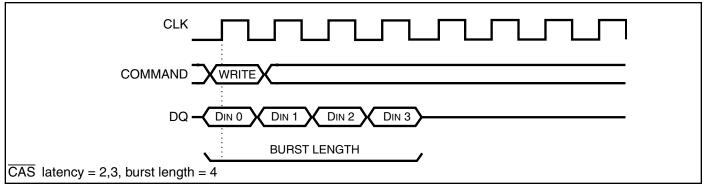
#### **Burst Write**

The write cycle is started by executing the command. The address provided during write command execution is used as the starting address, and at the same time, data for this address is input in synchronization with the clock signal.

Next, data is input in other in synchronization with the clock signal. During this operation, data is written to address generated automatically by the device. This cycle terminates automatically after a number of clock cycles determined by the stipulated burst length. However, the case where the burst length is a full page is an exception. In this case the write cycle must be terminated by executing a burst stop command. The latency for DQ pin data input

is zero, regardless of the CAS latency setting. However, a wait period (write recovery: tDPL) after the last data input is required for the device to complete the write operation.

Note that the upper byte and lower byte input data can be masked independently under control of the signals applied to the U/LDQM pins. The delay period (tDMD) is fixed at zero, regardless of the CAS latency setting, when this function is used.





#### Read With Auto-Precharge

The read with auto-precharge command first executes a burst read operation and then puts the selected bank in the precharged state automatically. After the precharge completes, the bank goes to the idle state. Thus this command performs a read command and a precharge command in a single operation.

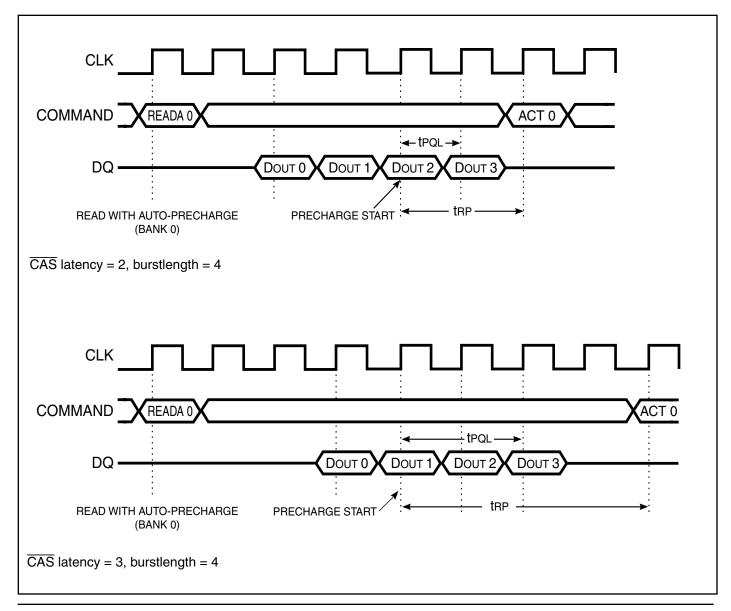
During this operation, the delay period (tPQL) between the last burst data output and the start of the precharge operation differs depending on the  $\overline{CAS}$  latency setting.

When the  $\overline{CAS}$  latency setting is two, the precharge operation starts on one clock cycle before the last burst data is output (tPQL = -1). When the  $\overline{CAS}$  latency setting is three, the precharge operation starts on two clock cycles before the last burst data is output (tPQL = -2). Therefore, the selected bank can be made active after a delay of tRP from the start position of this precharge operation.

The selected bank must be set to the active state before executing this command.

The auto-precharge function is invalid if the burst length is set to full page.

CAS Latency	3	2	
<b>t</b> PQL	-2	-1	





#### Write With Auto-Precharge

The write with auto-precharge command first executes a burst write operation and then puts the selected bank in the precharged state automatically. After the precharge completes the bank goes to the idle state. Thus this command performs a write command and a precharge command in a single operation.

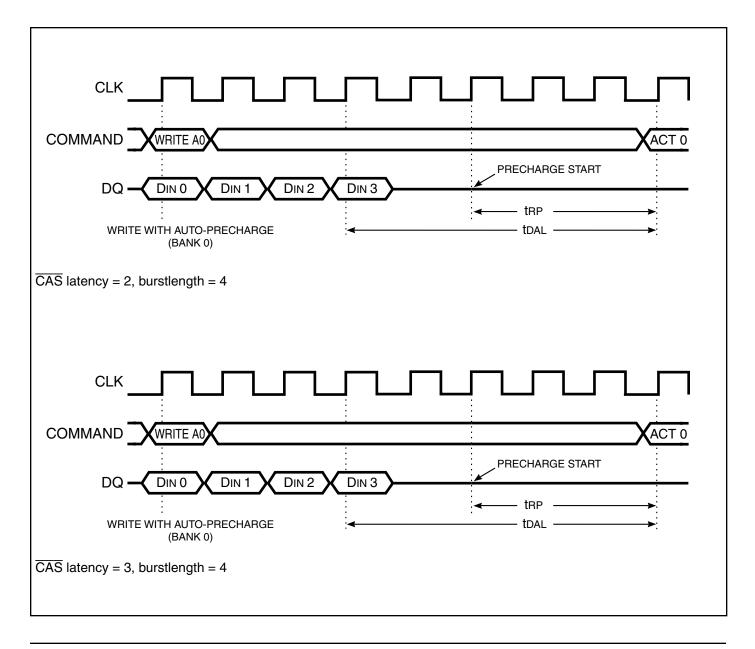
During this operation, the delay period (tDAL) between the last burst data input and the completion of the precharge operation differs depending on the  $\overline{CAS}$  latency setting. The delay (tDAL) is tRP plus two CLK periods. That is, the precharge operation starts two clock periods after the last burst data input.

Therefore, the selected bank can be made active after a delay of tDAL.

The selected bank must be set to the active state before executing this command.

The auto-precharge function is invalid if the burst length is set to full page.

CAS Latency	3	2	
tdal	2CLK	2CLK	
	+tRP	+tRP	



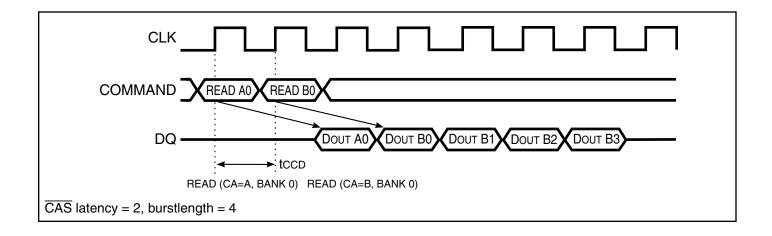


#### **Interval Between Read Command**

A new command can be executed while a read cycle is in progress, i.e., before that cycle completes. When the second read command is executed, after the  $\overline{CAS}$  latency has elapsed, data corresponding to the new read command is output in place of the data due to the previous read command.

The interval between two read command (tccd) must be at least one clock cycle.

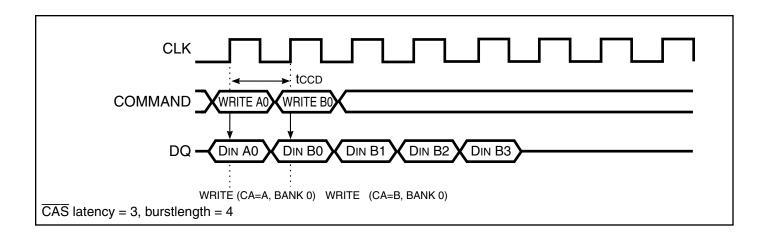
The selected bank must be set to the active state before executing this command.



#### **Interval Between Write Command**

A new command can be executed while a write cycle is in progress, i.e., before that cycle completes. At the point the second write command is executed, data corresponding to the new write command can be input in place of the data for the previous write command.

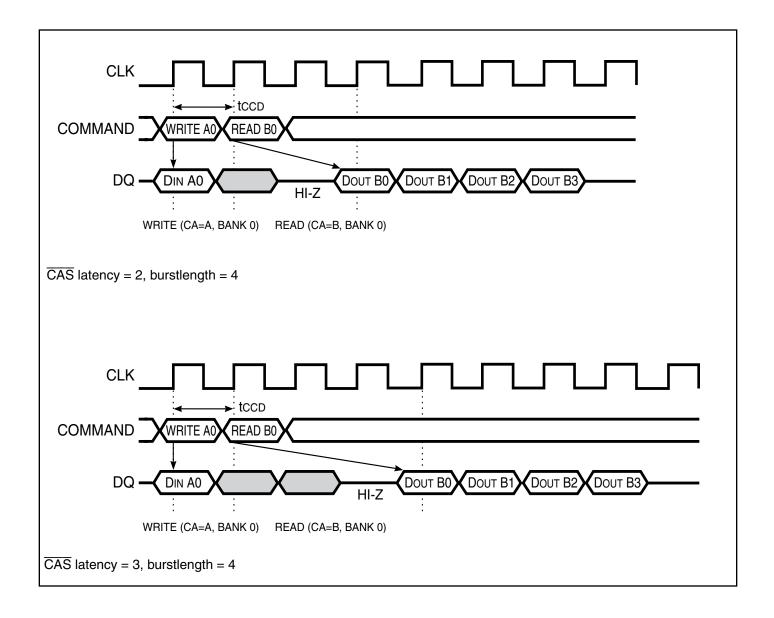
The interval between two write commands (tccd) must be at least one clock cycle.



#### Interval Between Write and Read Commands

A new read command can be executed while a write cycle is in progress, i.e., before that cycle completes. Data corresponding to the new read command is output after the CAS latency has elapsed from the point the new read command was executed. The I/On pins must be placed in the HIGH impedance state at least one cycle before data is output during this operation.

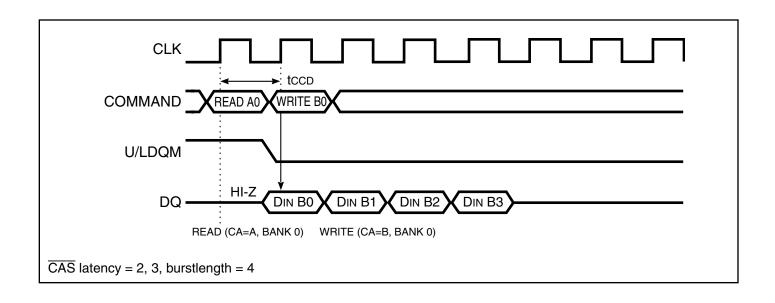
The interval (tccd) between command must be at least one clock cycle.





### Interval Between Read and Write Commands

A read command can be interrupted and a new write command executed while the read cycle is in progress, i.e., before that cycle completes. Data corresponding to the new write command can be input at the point new write command is executed. To prevent collision between input and output data at the DQn pins during this operation, the output data must be masked using the U/LDQM pins. The interval (tccd) between these commands must be at least one clock cycle.





## Precharge

The precharge command sets the bank selected by pin A11 to the precharged state. This command can be executed at a time tRAS following the execution of an active command to the same bank. The selected bank goes to the idle state at a time tRP following the execution of the precharge command, and an active command can be executed again for that bank.

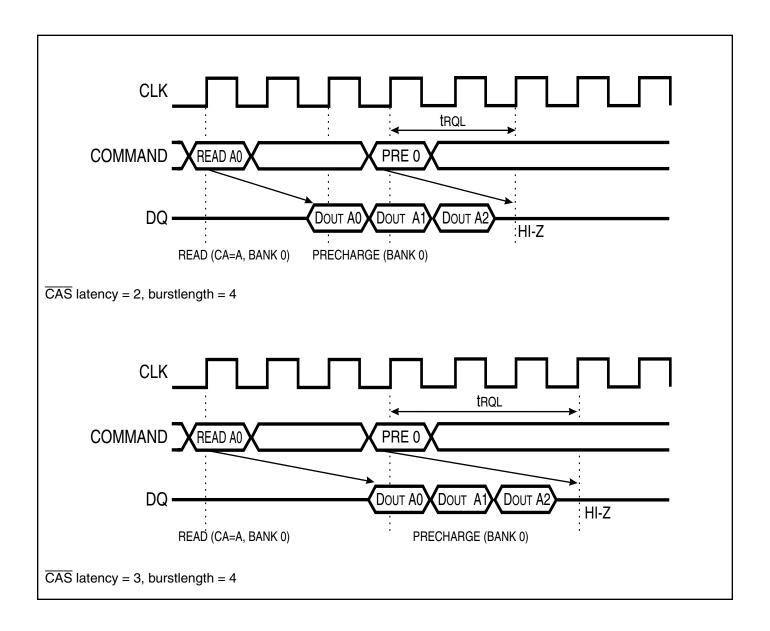
If pin A10 is low when this command is executed, the bank selected by pin A11 will be precharged, and if pin A10 is HIGH, both banks will be precharged at the same time. This input to pin A11 is ignored in the latter case.

## **Read Cycle Interruption**

#### **Using the Precharge Command**

A read cycle can be interrupted by the execution of the precharge command before that cycle completes. The delay time (t<sub>RQL</sub>) from the execution of the precharge command to the completion of the burst output is the clock cycle of  $\overline{CAS}$  latency.

CAS Latency	3	2	
trql	3	2	





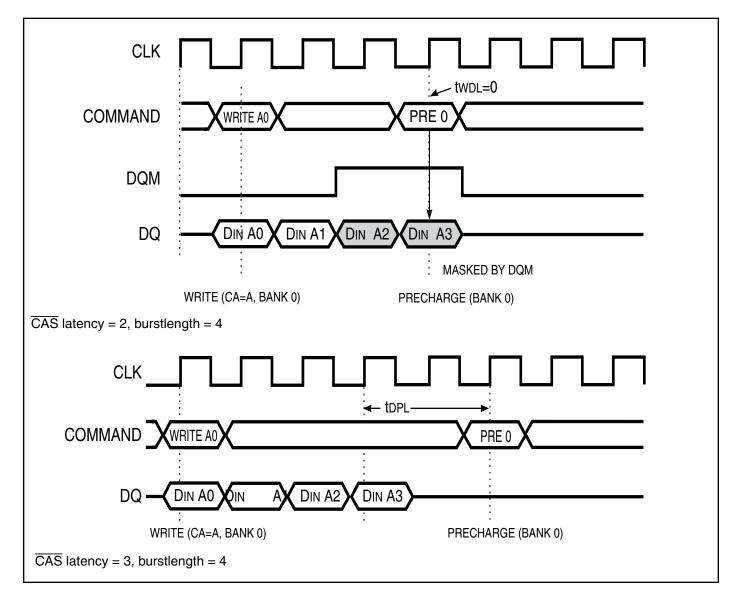
## Write Cycle Interruption Using the Precharge Command

A write cycle can be interrupted by the execution of the precharge command before that cycle completes. The delay time (twDL) from the precharge command to the point where burst input is invalid, i.e., the point where input data is no longer written to device internal memory is zero clock cycles regardless of the  $\overline{CAS}$ .

To inhibit invalid write, the DQM signal must be asserted HIGH with the precharge command.

This precharge command and burst write command must be of the same bank, otherwise it is not precharge interrupt but only another bank precharge of dual bank operation. Inversely, to write all the burst data to the device, the precharge command must be executed after the write data recovery period (tDPL) has elapsed. Therefore, the precharge command must be executed two clock cycles after the input of the last burst data item.

CAS Latency	3	2	
twdl	0	0	
<b>t</b> DPL	2	2	



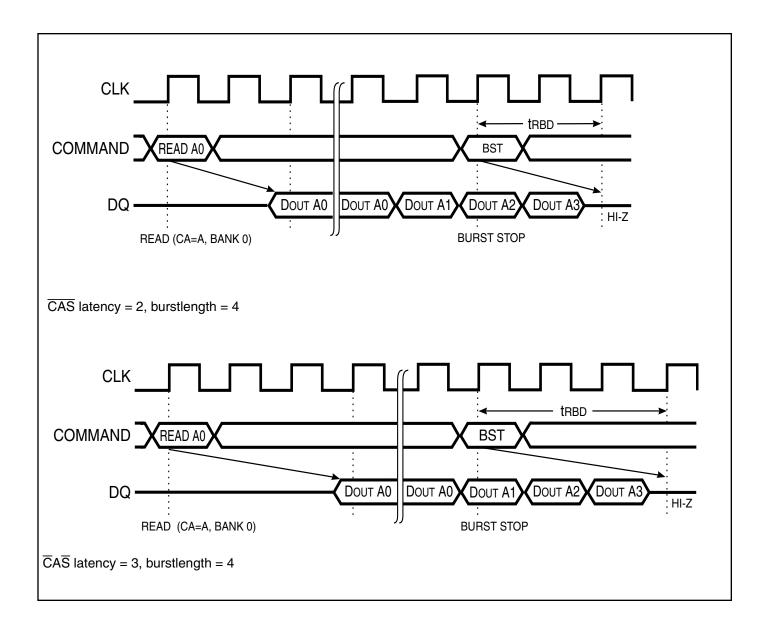


## Read Cycle (Full Page) Interruption Using the Burst Stop Command

The IS42/4516100H can output data continuously from the burst start address (a) to location a+255 during a read cycle in which the burst length is set to full page. The IS42/4516100H repeats the operation starting at the 256th cycle with the data output returning to location (a) and continuing with a+1, a+2, a+3, etc. A burst stop command must be executed to terminate this cycle. A precharge command must be executed within the ACT to PRE command period (tRAS max.) following the burst stop command.

After the period (tRBD) required for burst data output to stop following the execution of the burst stop command has elapsed, the outputs go to the HIGH impedance state. This period (tRBD) is two clock cycle when the CAS latency is two and three clock cycle when the CAS latency is three.

CAS Latency	3	2
trbd	3	2

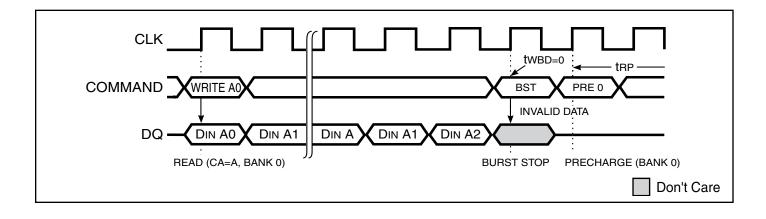




# Write Cycle (Full Page) Interruption Using the Burst Stop Command

The DRAM can input data continuously from the burst start address (a) to location a+255 during a write cycle in which the burst length is set to full page. The DRAM repeats the operation starting at the 256th cycle with data input returning to location (a) and continuing with a+1, a+2, a+3, etc. A burst stop command must be executed to terminate this cycle. A precharge command

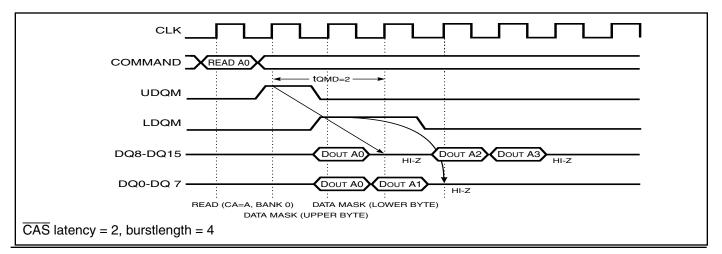
must be executed within the ACT to PRE command period (t<sub>RAS</sub> max.) following the burst stop command. After the period (t<sub>WBD</sub>) required for burst data input to stop following the execution of the burst stop command has elapsed, the write cycle terminates. This period (t<sub>WBD</sub>) is zero clock cycles, regardless of the CAS latency.



## Burst Data Interruption Using the U/LDQM Pins (Read Cycle)

Burst data output can be temporarily interrupted (masked) during a read cycle using the U/LDQM pins. Regardless of the CAS latency, two clock cycles (tQMD) after one of the U/LDQM pins goes HIGH, the corresponding outputs go to the HIGH impedance state. Subsequently, the outputs are maintained in the high impedance state as long as that U/LDQM pin remains HIGH. When the U/LDQM pin goes LOW, output is resumed at a time tQMD later. This output control operates independently on a byte basis with the UDQM pin controlling upper byte output (pins DQ8-DQ15) and the LDQM pin controlling lower byte output (pins DQ0 to DQ7).

Since the U/LDQM pins control the device output buffers only, the read cycle continues internally and, in particular, incrementing of the internal burst counter continues.



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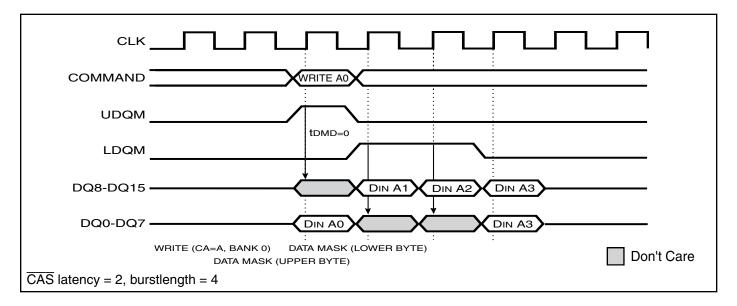
# Burst Data Interruption U/LDQM Pins (Write Cycle)

Burst data input can be temporarily interrupted (muted ) during a write cycle using the U/LDQM pins. Regardless of the CAS latency, as soon as one of the U/LDQM pins goes HIGH, the corresponding externally applied input data will no longer be written to the device internal circuits. Subsequently, the corresponding input continues to be muted as long as that U/LDQM pin remains HIGH.

The DRAM will revert to accepting input as soon as

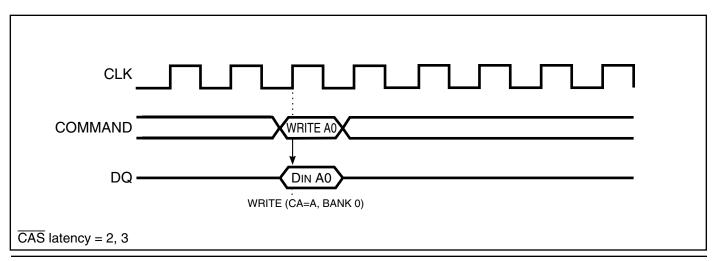
that pin is dropped to LOW and data will be written to the device. This input control operates independently on a byte basis with the UDQM pin controlling upper byte input (pin DQ8 to DQ15) and the LDQM pin controlling the lower byte input (pins DQ0 to DQ7).

Since the U/LDQM pins control the device input buffers only, the cycle continues internally and, in particular, incrementing of the internal burst counter continues.



# **Burst Read and Single Write**

The burst read and single write mode is set up using the mode register set command. During this operation, the burst read cycle operates normally, but the write cycle only writes a single data item for each write cycle. The  $\overline{CAS}$  latency and DQM latency are the same as in normal mode.

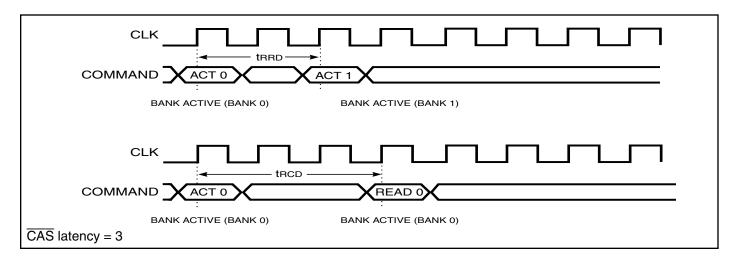




#### Bank Active Command Interval

When the selected bank is precharged, the period trp has elapsed and the bank has entered the idle state, the bank can be activated by executing the active command. If the other bank is in the idle state at that time, the active command can be executed for that bank after the period tRRD has elapsed. At that point both banks will be in the active state. When a bank active command has been executed, a precharge command must be executed for that bank within the ACT to PRE command period (tRAS max). Also note that a precharge command cannot be executed for an active bank before tRAS (min) has elapsed.

After a bank active command has been executed and the trcd period has elapsed, read write (including autoprecharge) commands can be executed for that bank.

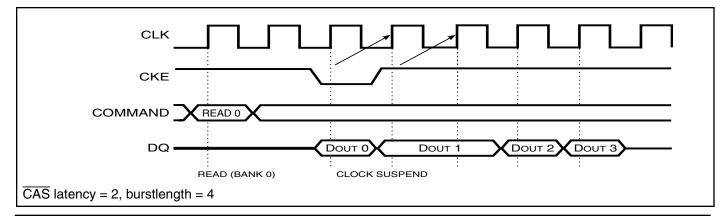


## **Clock Suspend**

When the CKE pin is dropped from HIGH to LOW during a read or write cycle, the DRAM enters clock suspend mode on the next CLK rising edge. This command reduces the device power dissipation by stopping the device internal clock. Clock suspend mode continues as long as the CKE pin remains low. In this state, all inputs other than CKE pin are invalid and no other commands can be executed. Also, the device internal states are maintained. When the CKE pin goes from LOW to HIGH clock suspend mode is terminated on the next CLK rising edge and device operation resumes.

The next command cannot be executed until the recovery period (tcka) has elapsed.

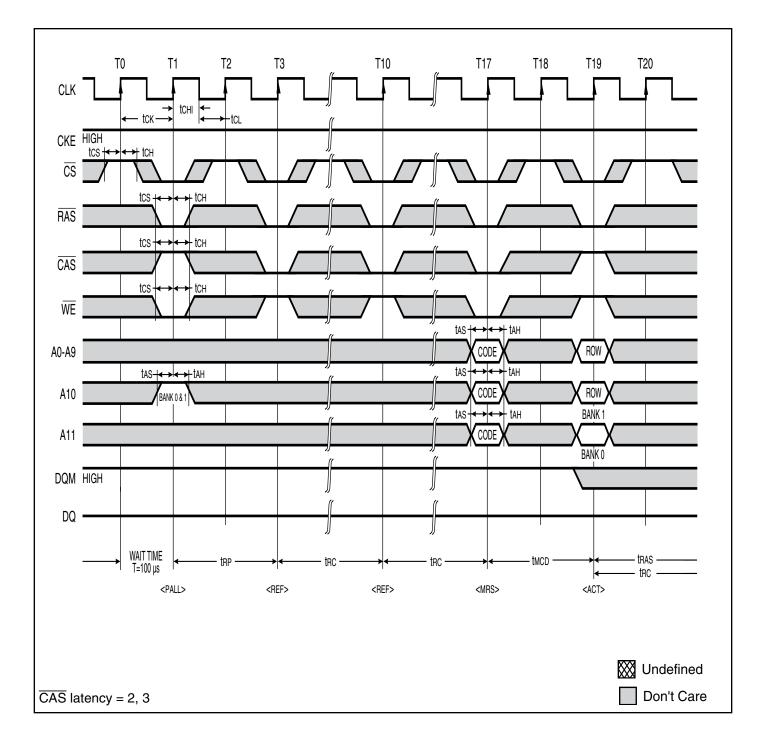
Since this command differs from the self-refresh command described previously in that the refresh operation is not performed automatically internally, the refresh operation must be performed within the refresh period (tref). Thus the maximum time that clock suspend mode can be held is just under the refresh cycle time.





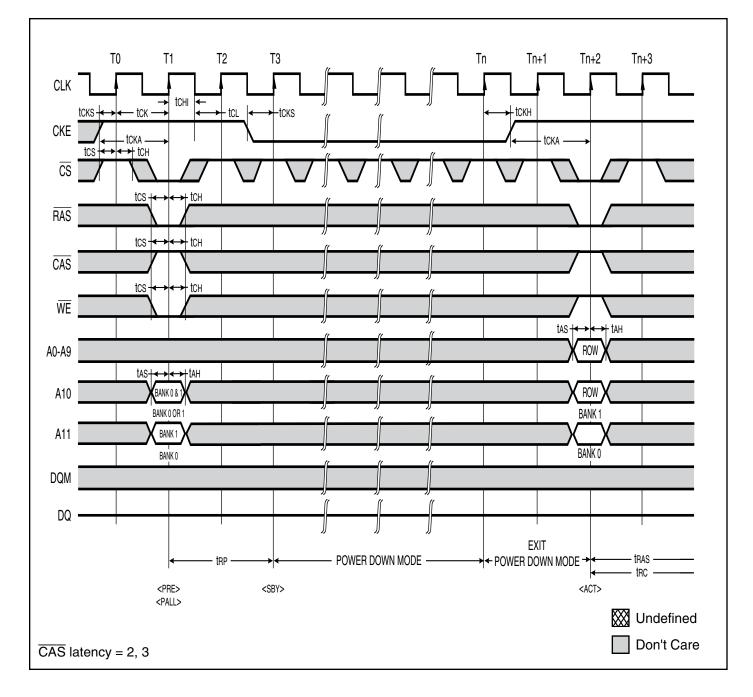
# **OPERATION TIMING EXAMPLE**

# Power-On Sequence, Mode Register Set Cycle



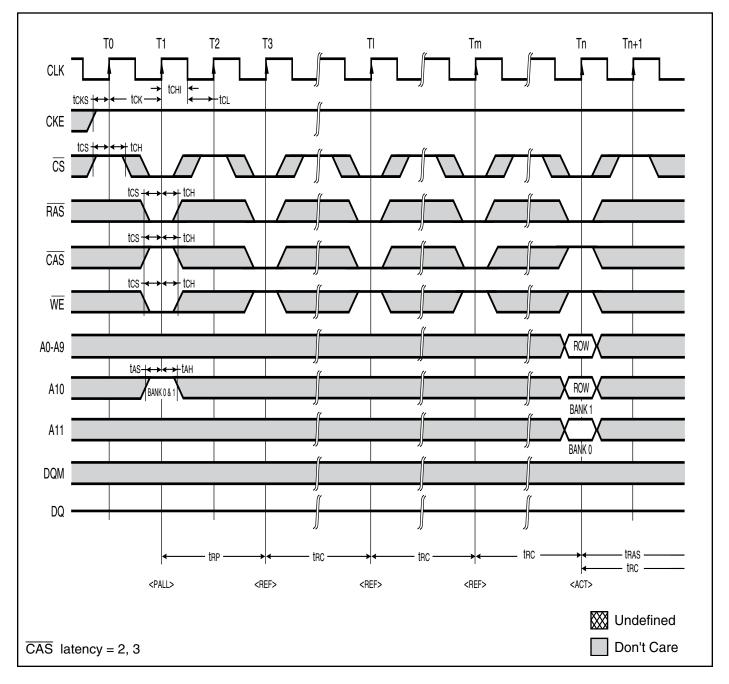


# Power-Down Mode Cycle



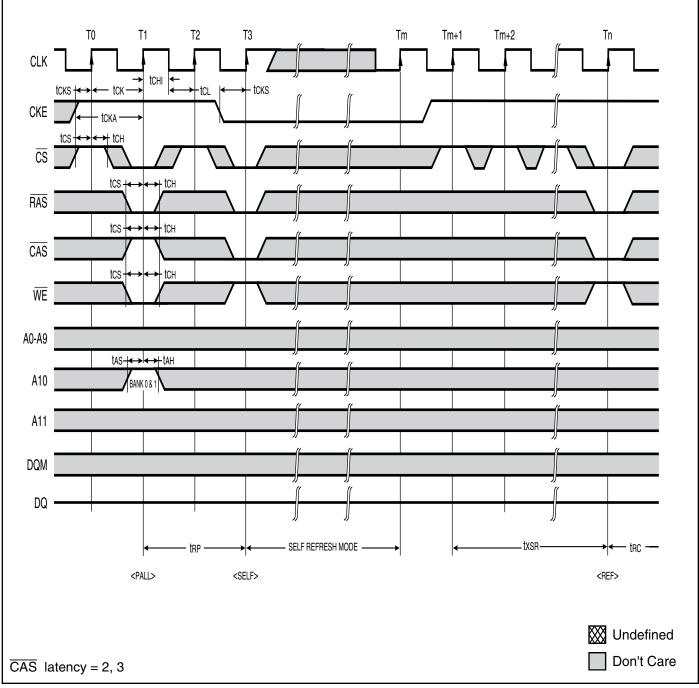


# **Auto-Refresh Cycle**





# Self-Refresh Cycle



Note:

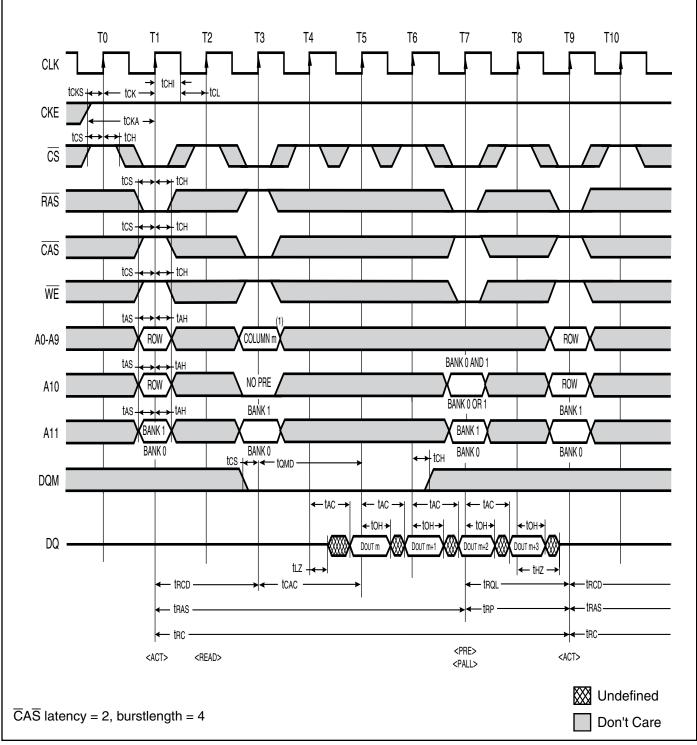
1: A8, A9 = Don't Care.

2. Self-Refresh Mode is not supported for A2 grade with  $T_A > 85^{\circ}C$ .

# IS42S16100H, IS45S16100H



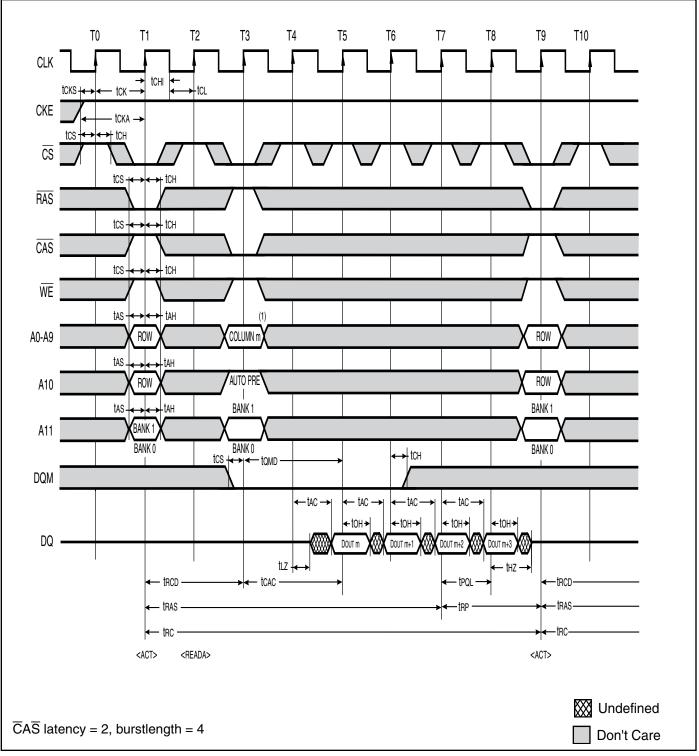
## **Read Cycle**



Note 1: A8,A9 = Don't Care.



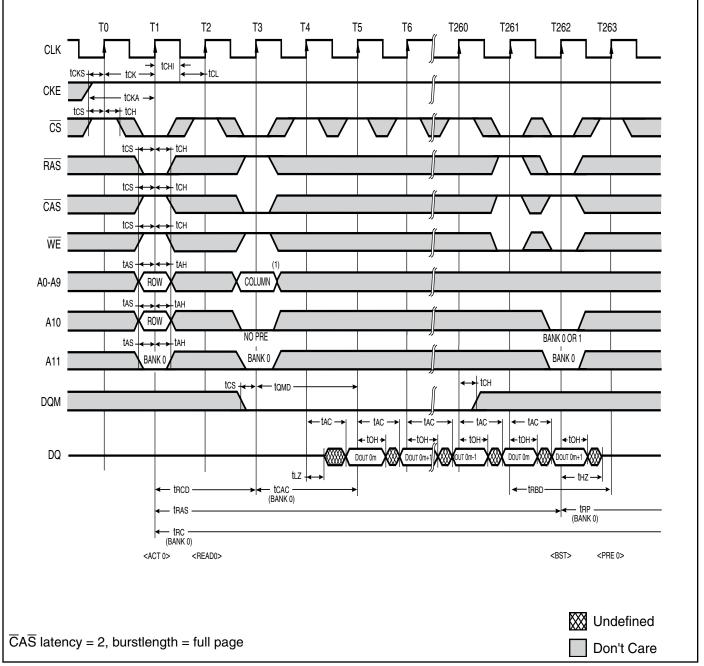
## Read Cycle / Auto-Precharge



Note 1: A8,A9 = Don't Care.



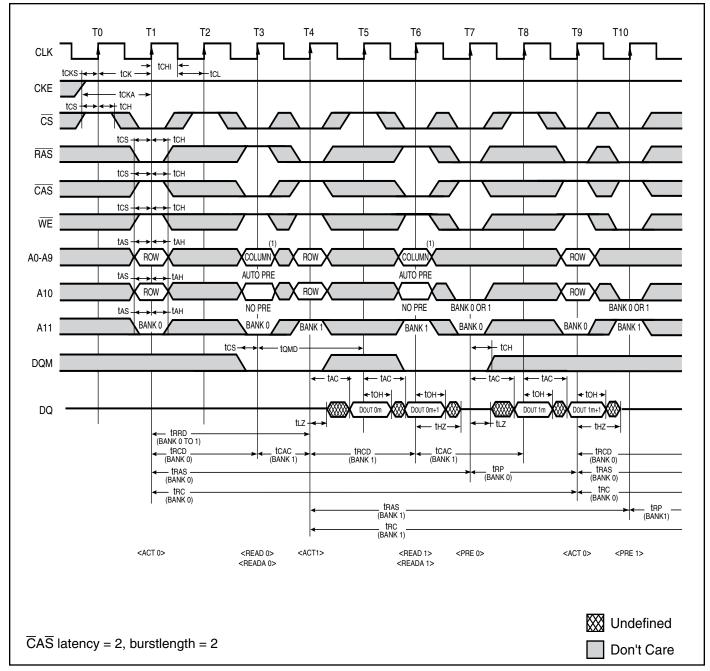
## Read Cycle / Full Page



Note 1: A8,A9 = Don't Care.



# Read Cycle / Ping-Pong Operation (Bank Switching)

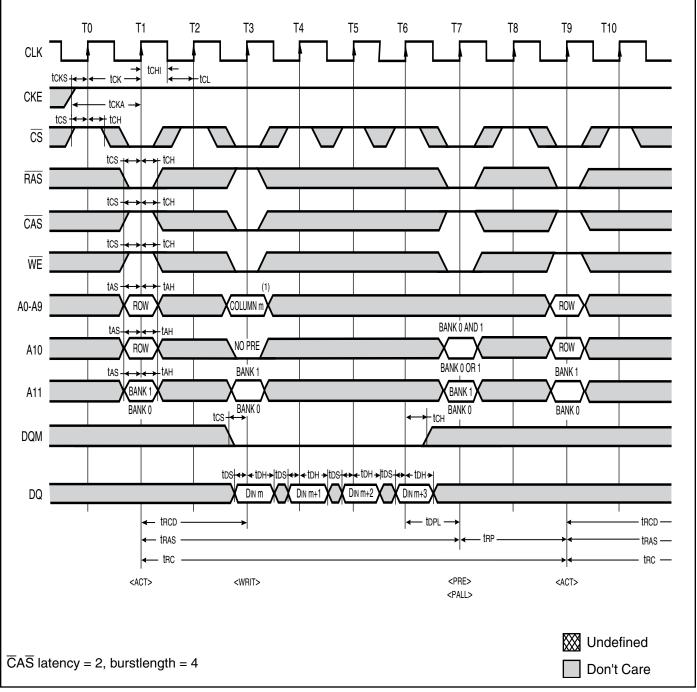


Note 1: A8,A9 = Don't Care.

# IS42S16100H, IS45S16100H



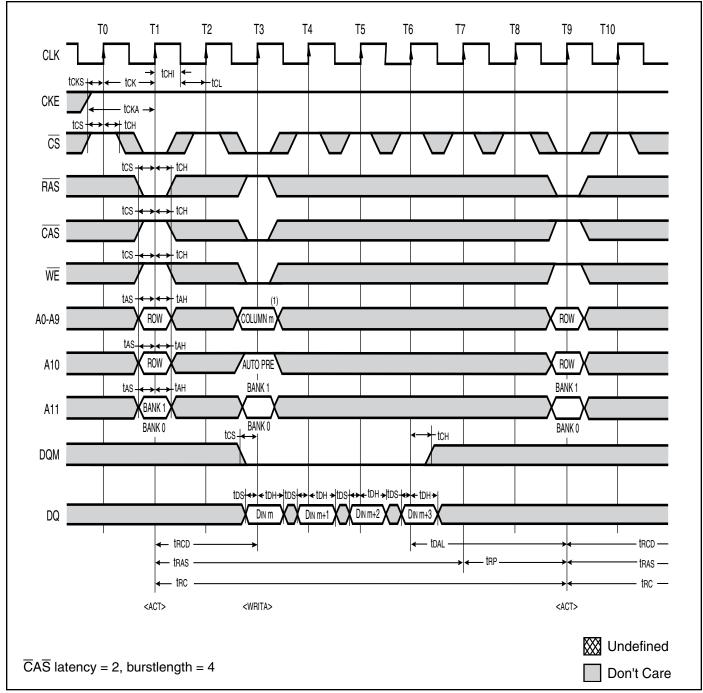
# Write Cycle



Note 1: A8,A9 = Don't Care.



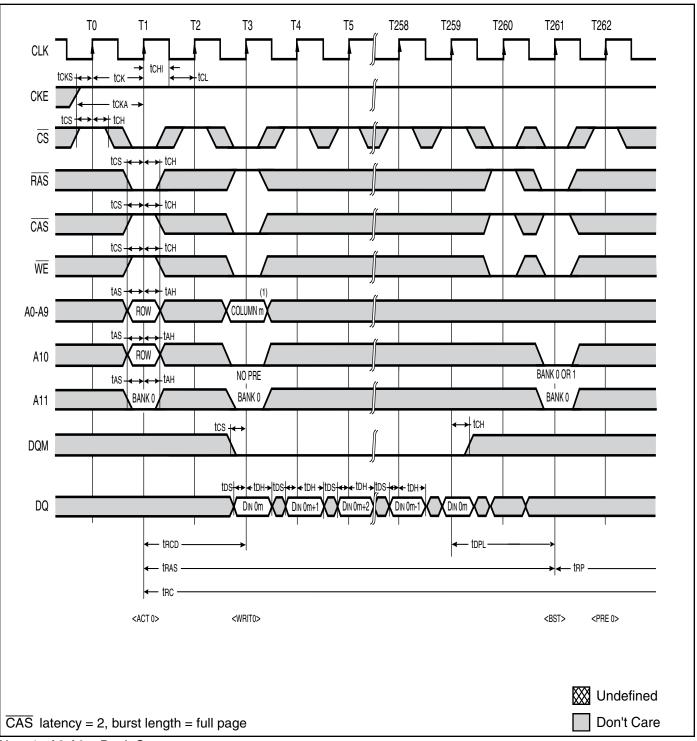
## Write Cycle / Auto-Precharge

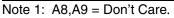


Note 1: A8,A9 = Don't Care.



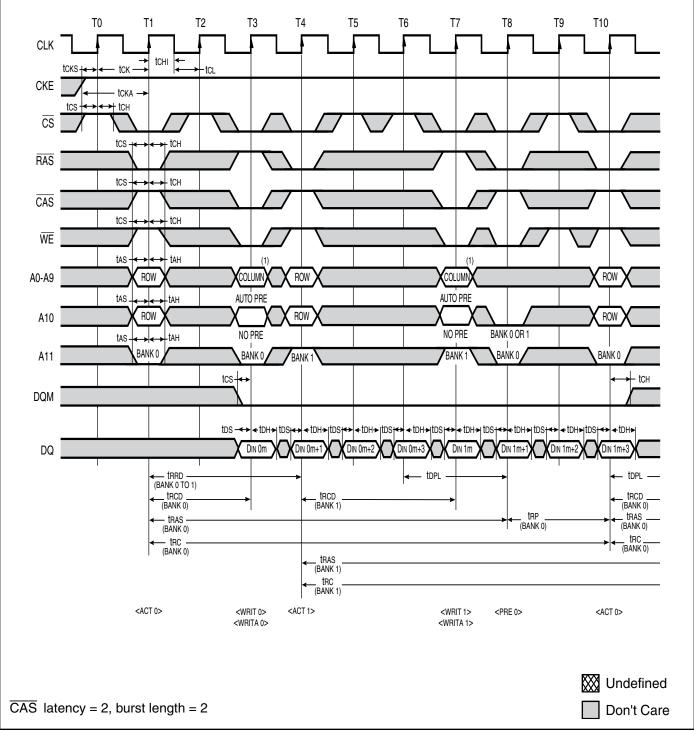
# Write Cycle / Full Page

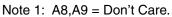






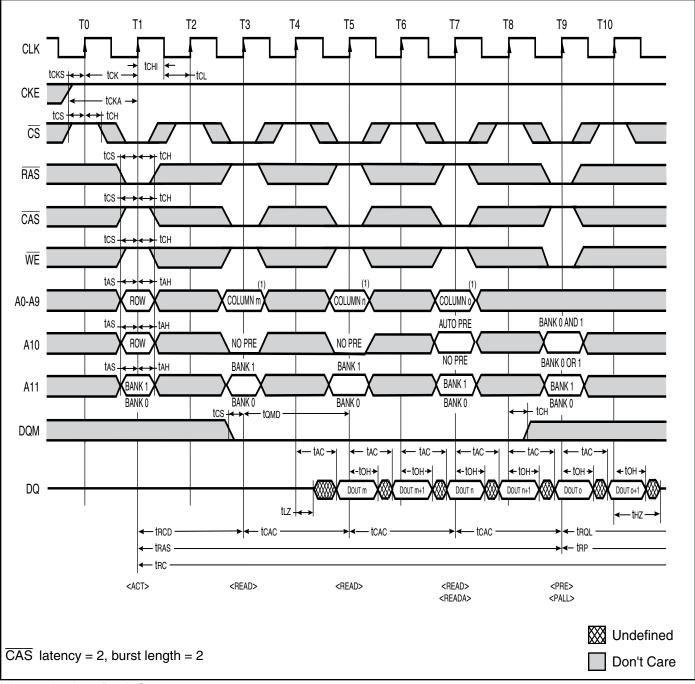
# Write Cycle / Ping-Pong Operation







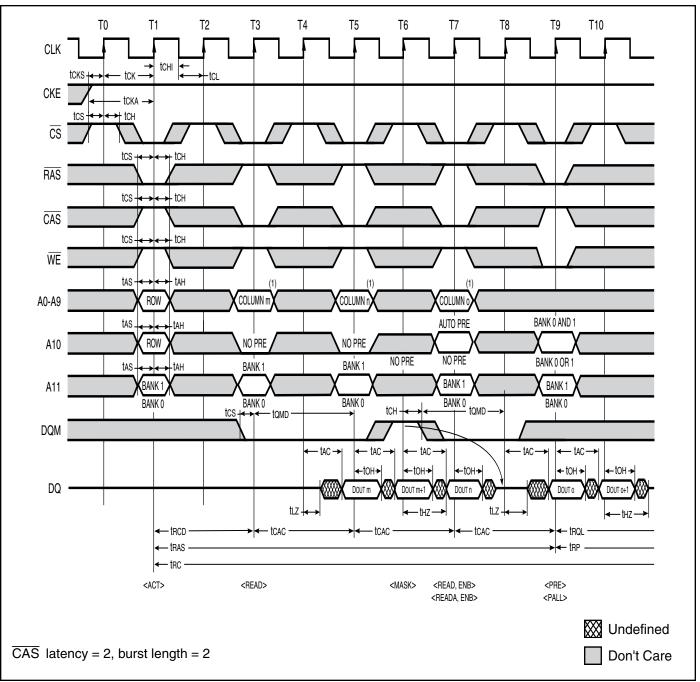
### Read Cycle / Page Mode



Note 1: A8,A9 = Don't Care.



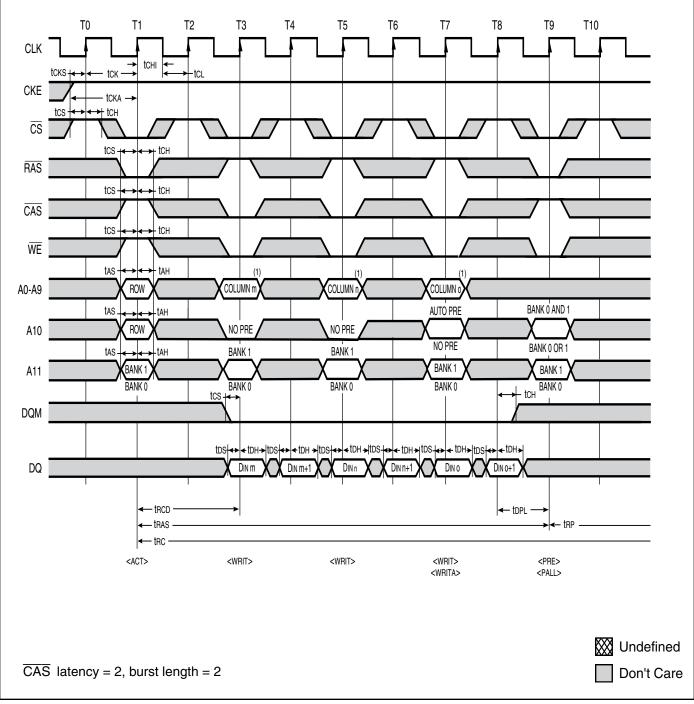
# Read Cycle / Page Mode; Data Masking



Note 1: A8,A9 = Don't Care.



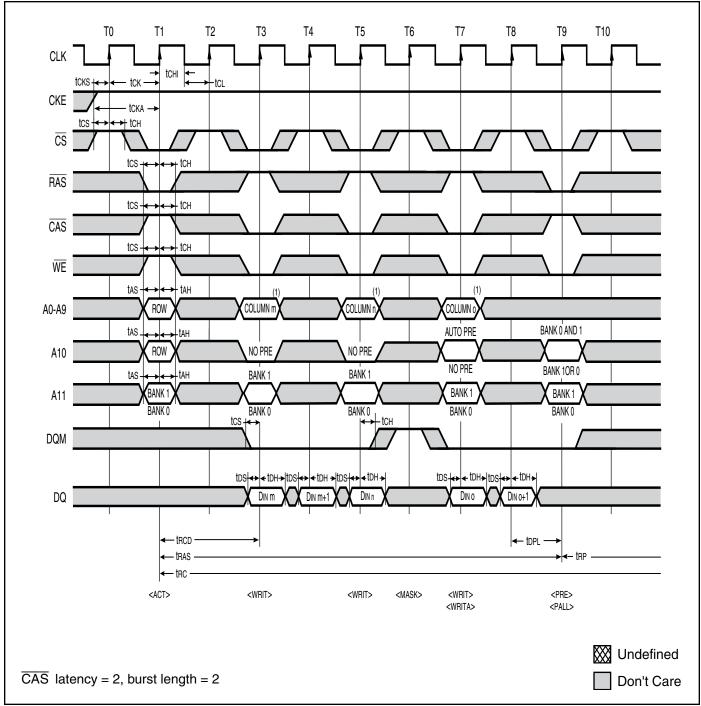
## Write Cycle / Page Mode



Note 1: A8,A9 = Don't Care.



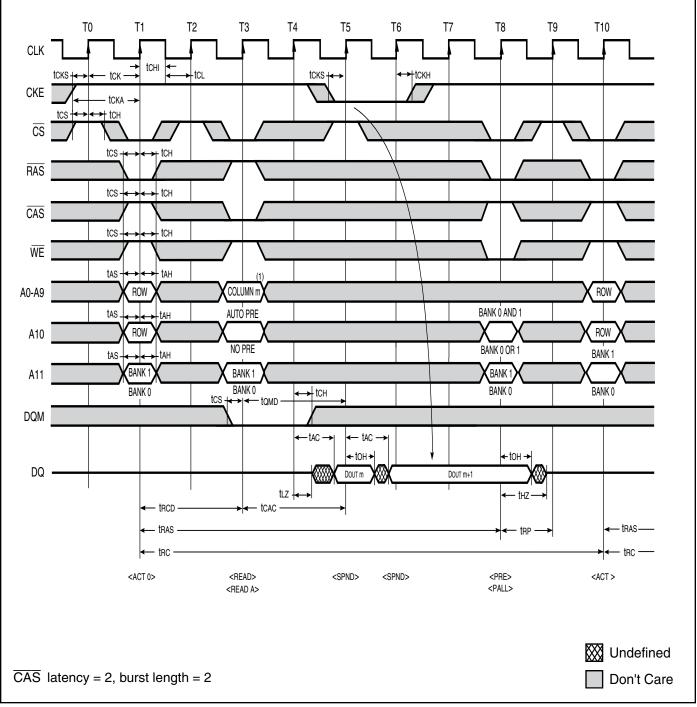
Write Cycle / Page Mode; Data Masking



Note 1: A8,A9 = Don't Care.



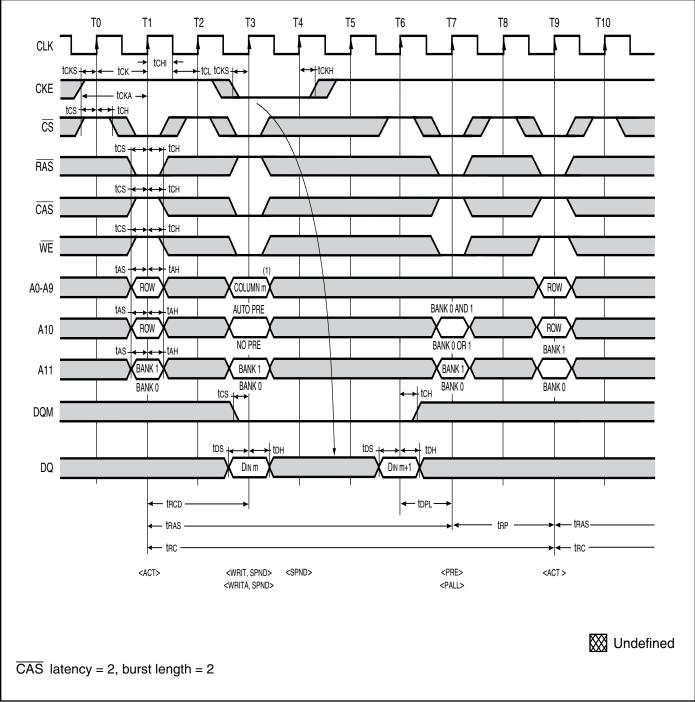
## Read Cycle / Clock Suspend



Note 1: A8,A9 = Don't Care.



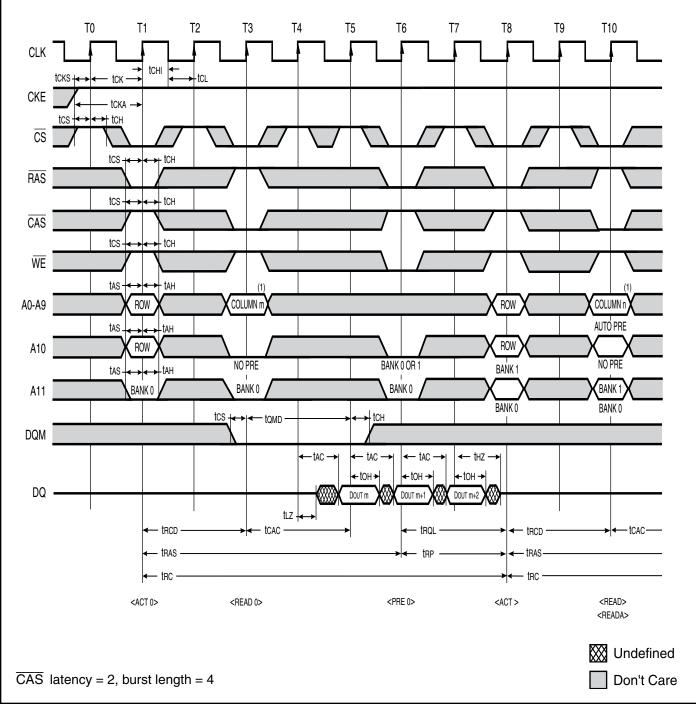
## Write Cycle / Clock Suspend

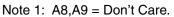


Note 1: A8,A9 = Don't Care.



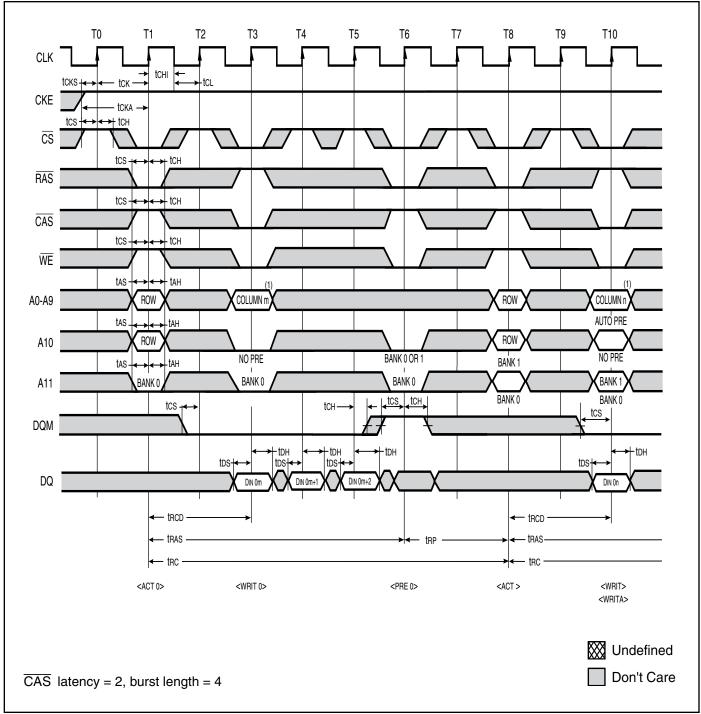
# Read Cycle / Precharge Termination







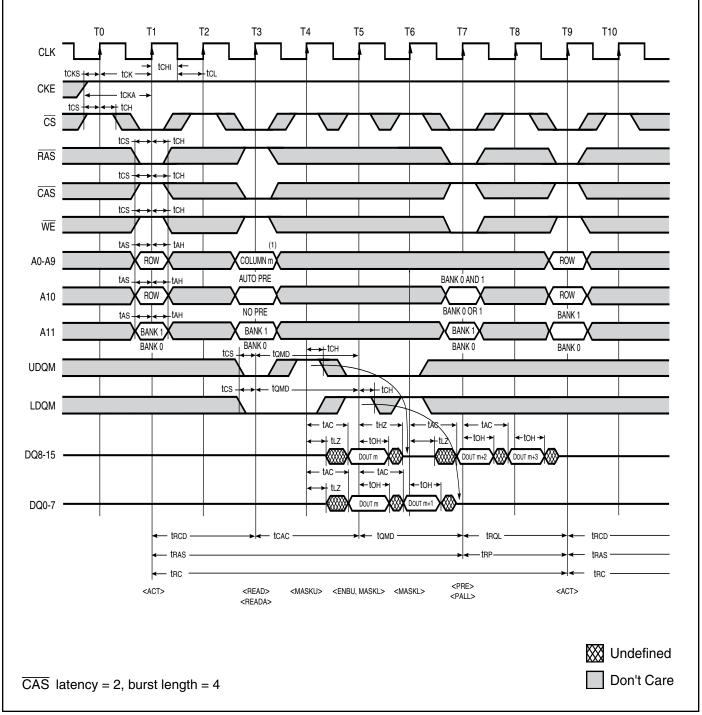
Write Cycle / Precharge Termination

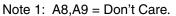


Note 1: A8,A9 = Don't Care.



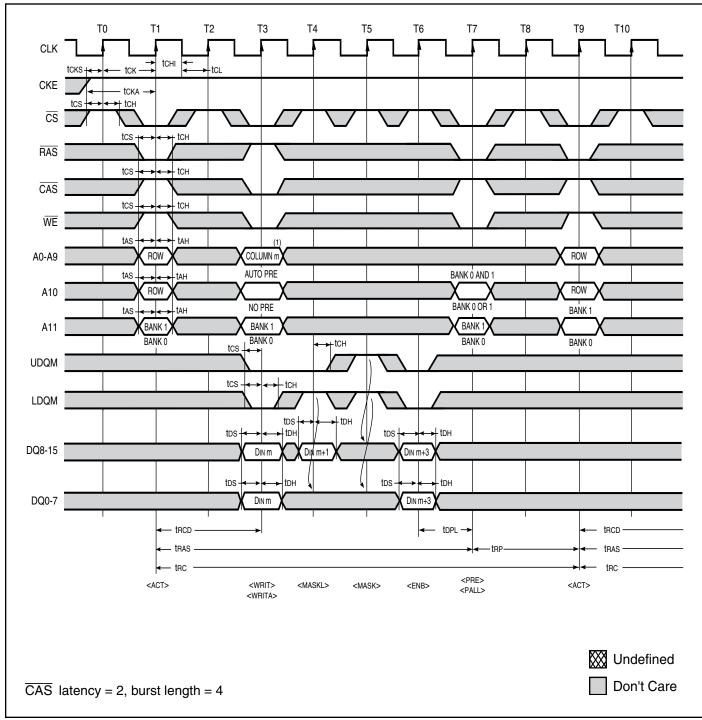
# **Read Cycle / Byte Operation**







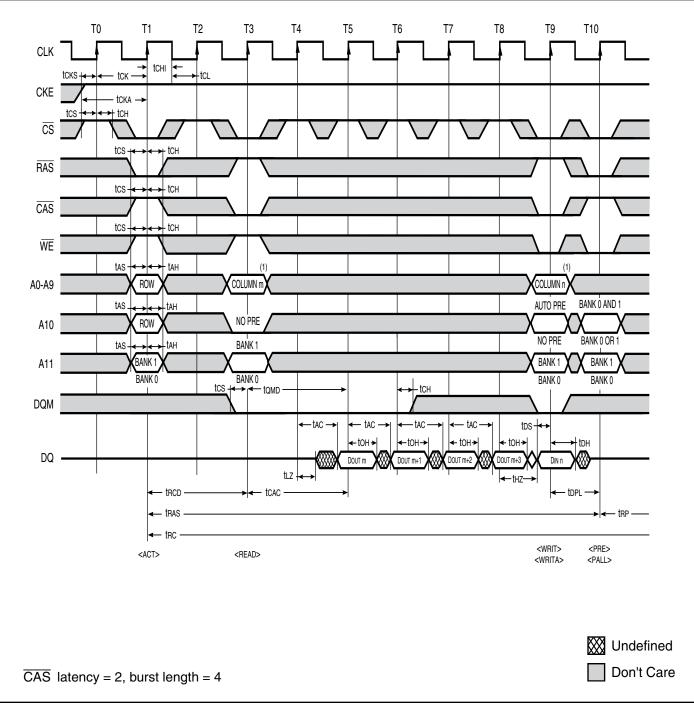
## Write Cycle / Byte Operation

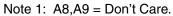


Note 1: A8,A9 = Don't Care.



# Read Cycle, Write Cycle / Burst Read, Single Write

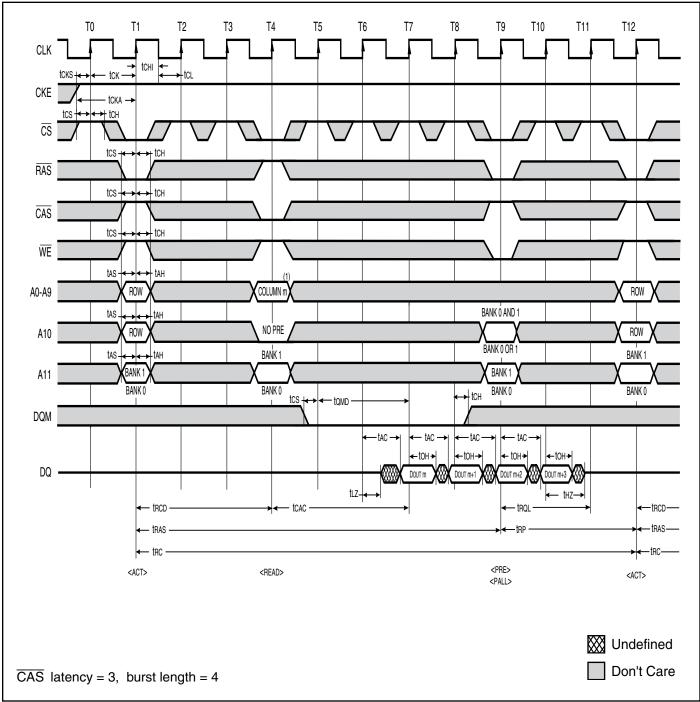




# IS42S16100H, IS45S16100H



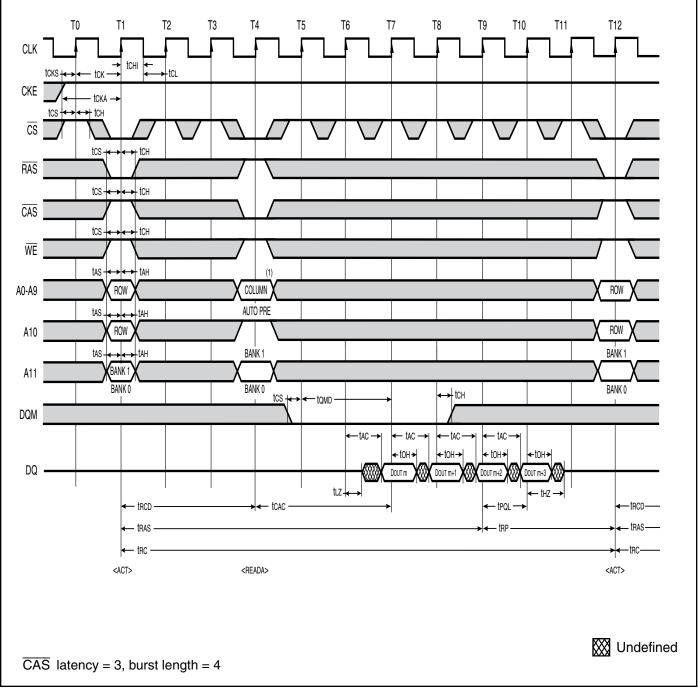
## **Read Cycle**

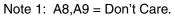


Note 1: A8,A9 = Don't Care.



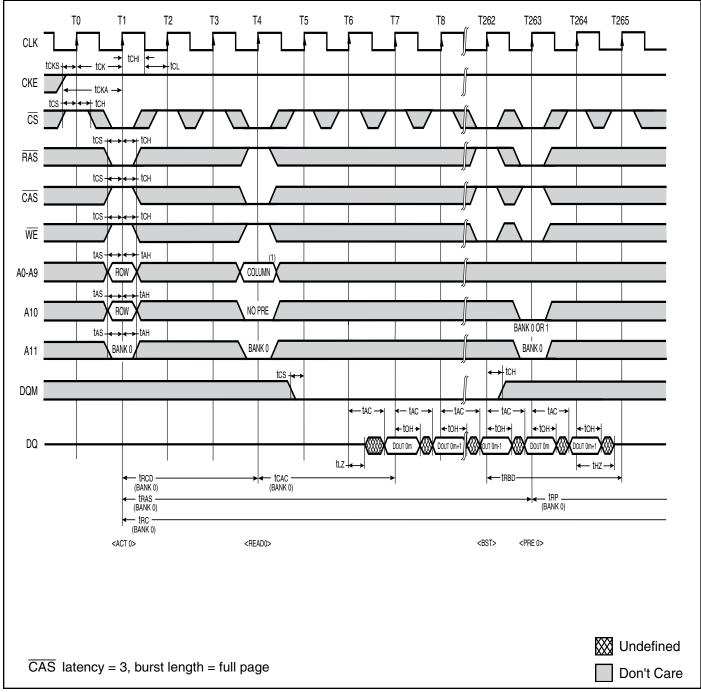
# Read Cycle / Auto-Precharge

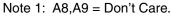






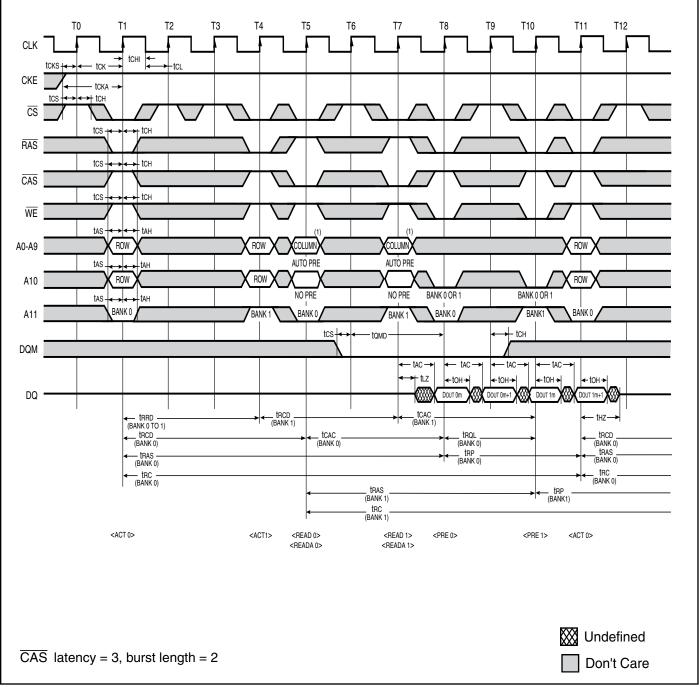
## Read Cycle / Full Page

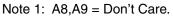








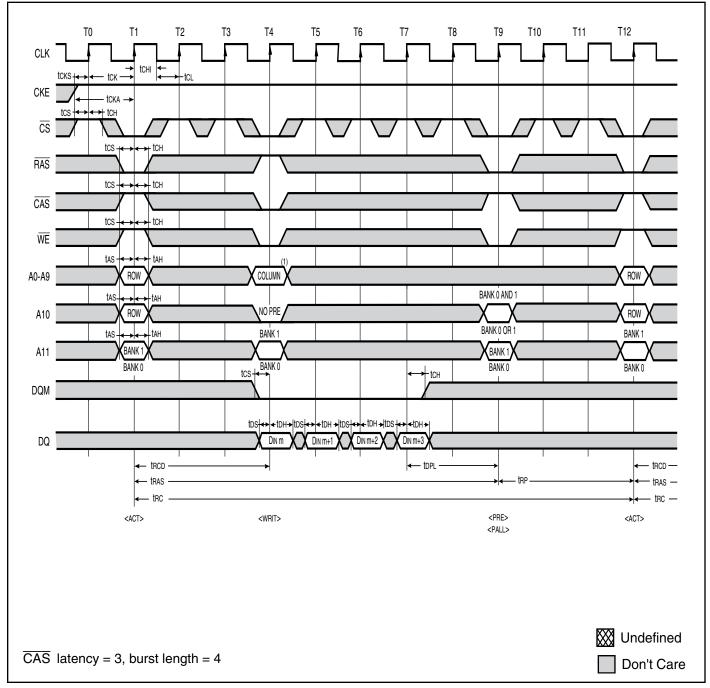




# IS42S16100H, IS45S16100H



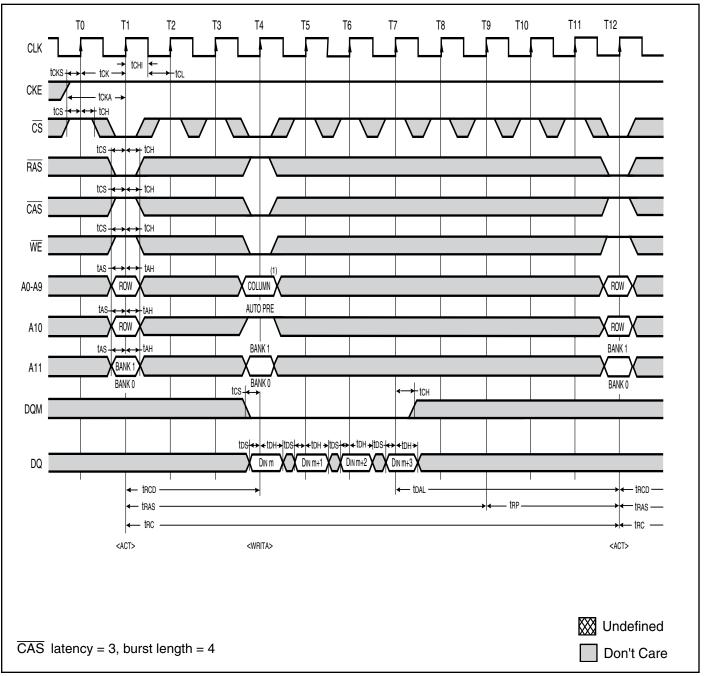
## Write Cycle



Note 1: A8,A9 = Don't Care.



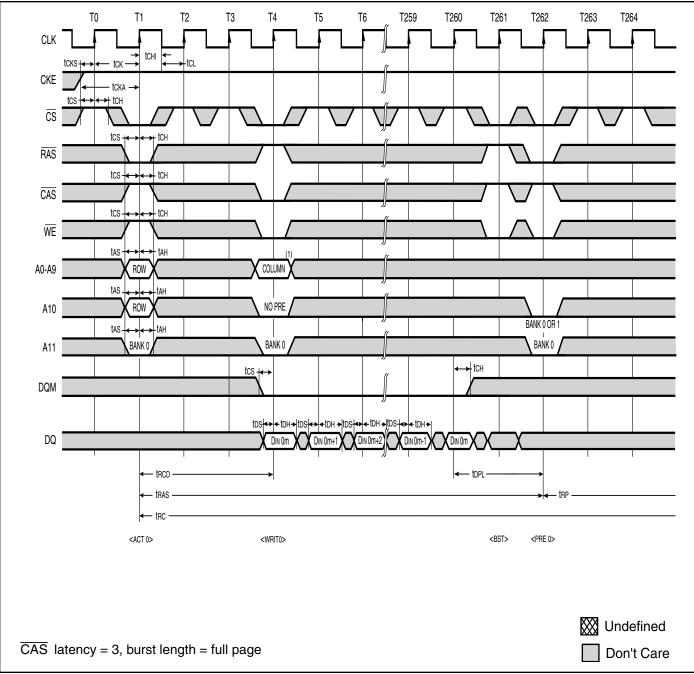
# Write Cycle / Auto-Precharge

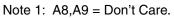


Note 1: A8,A9 = Don't Care.



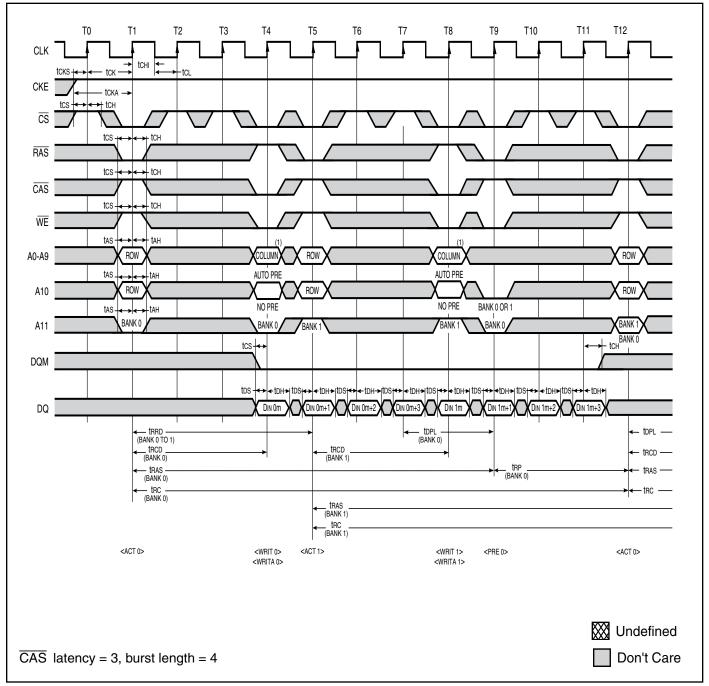
## Write Cycle / Full Page







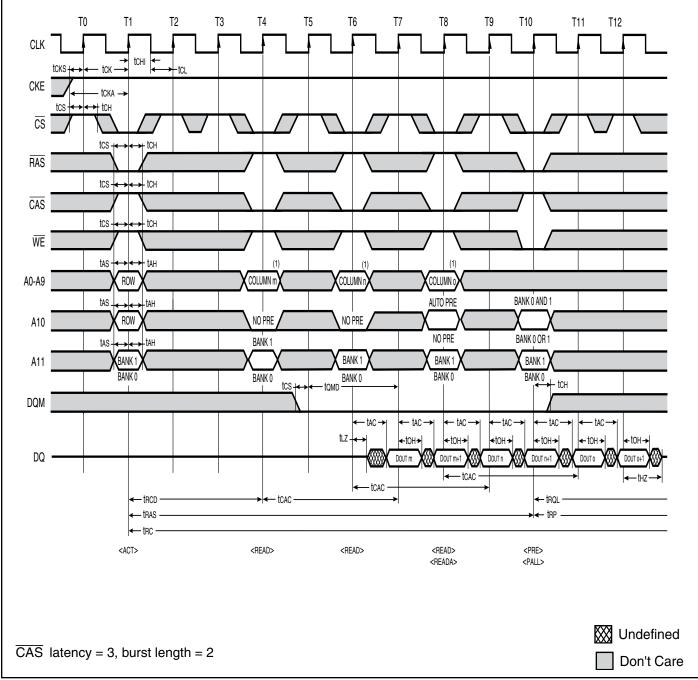




Note 1: A8,A9 = Don't Care.



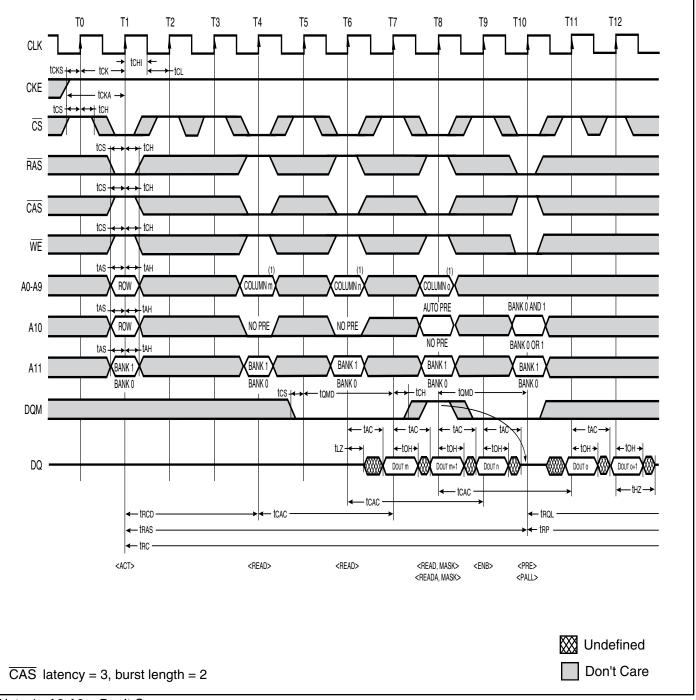
## Read Cycle / Page Mode



Note 1: A8,A9 = Don't Care.



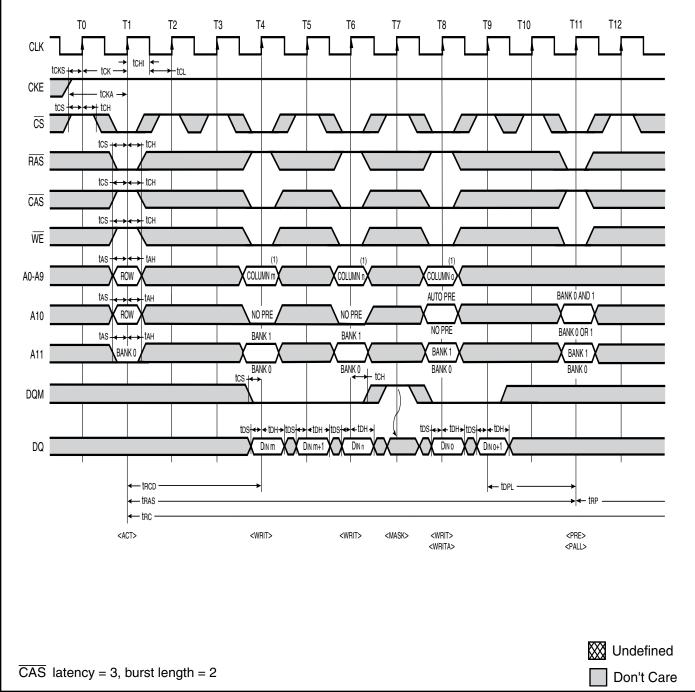
# Read Cycle / Page Mode; Data Masking



Note 1: A8,A9 = Don't Care.



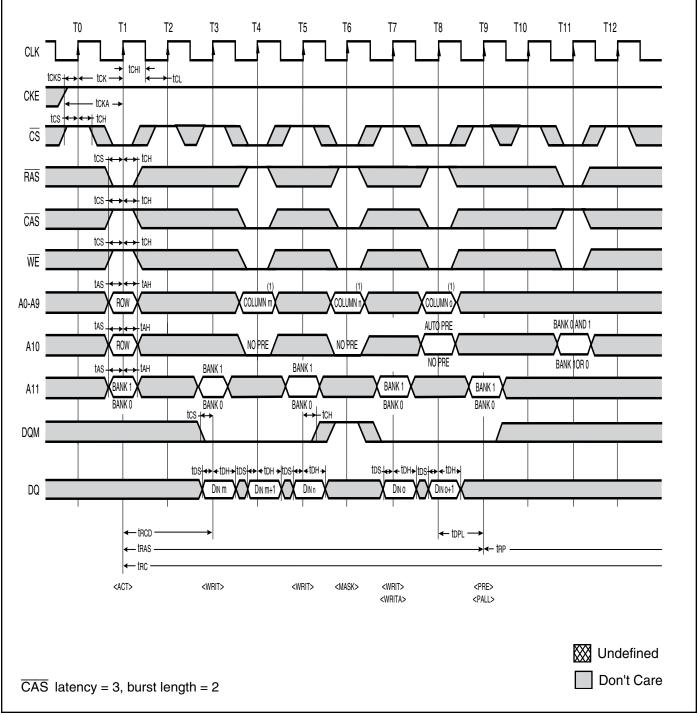
## Write Cycle / Page Mode

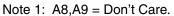


Note 1: A8,A9 = Don't Care.



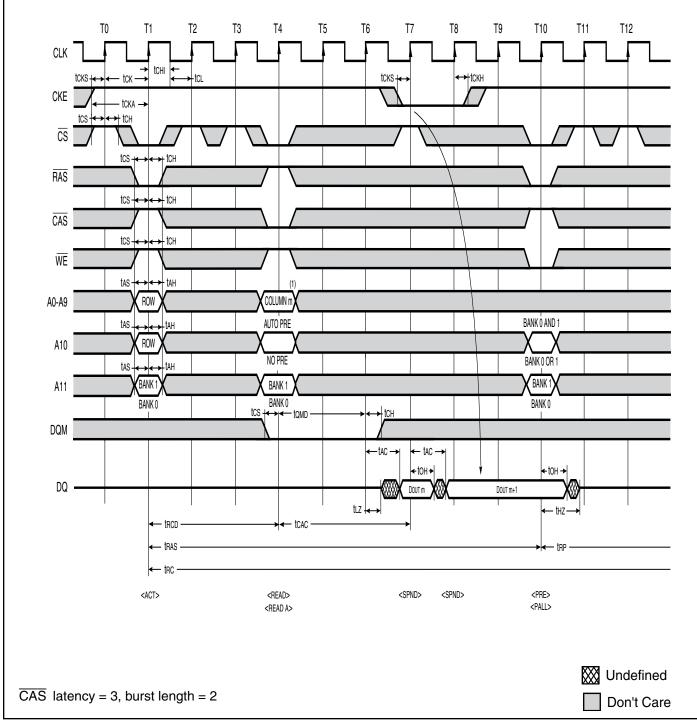
# Write Cycle / Page Mode; Data Masking







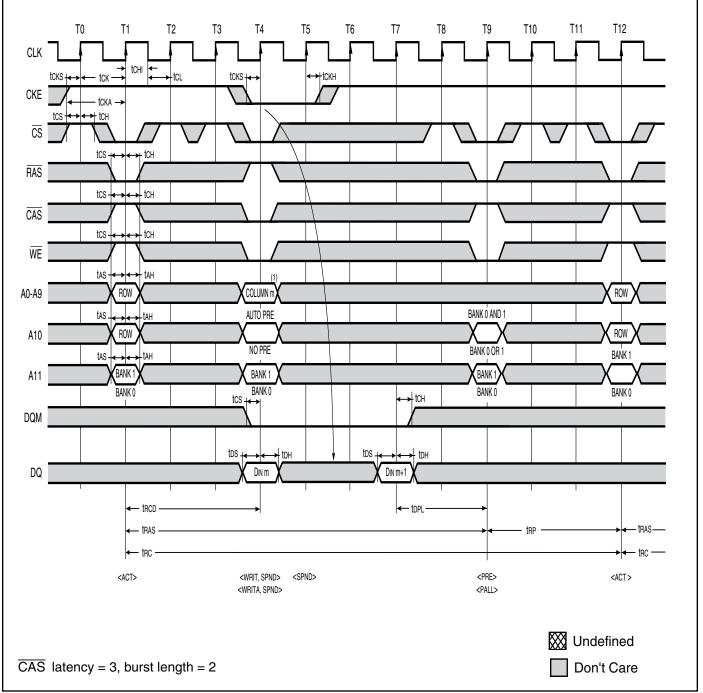
# Read Cycle / Clock Suspend

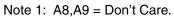


Note 1: A8,A9 = Don't Care.



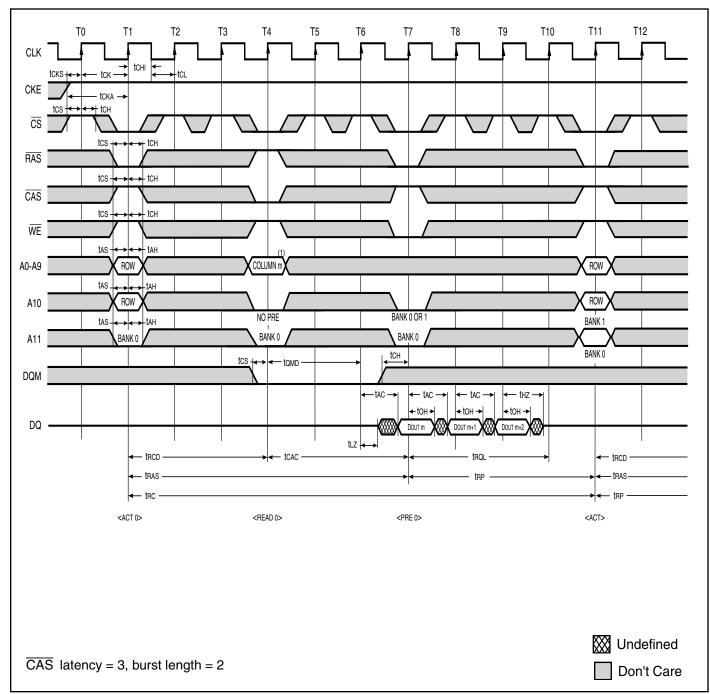
# Write Cycle / Clock Suspend







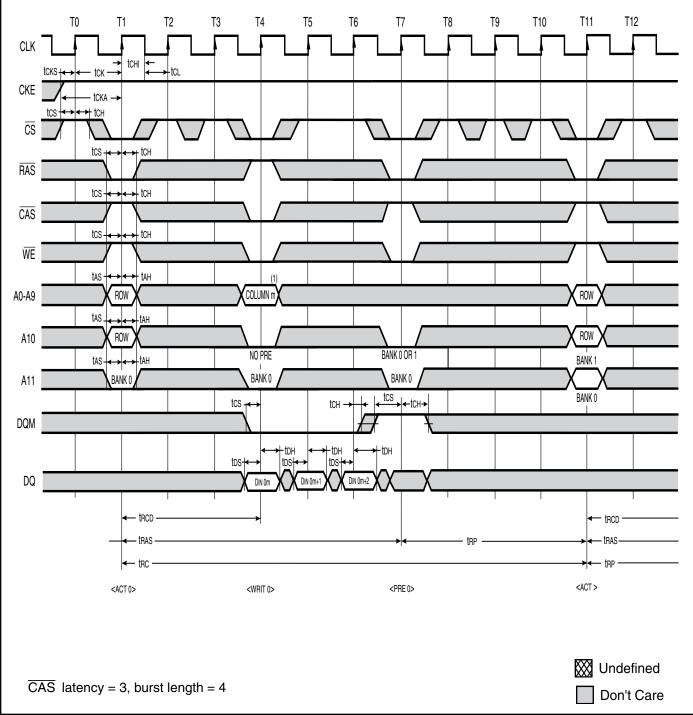
# Read Cycle / Precharge Termination

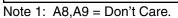


Note 1: A8,A9 = Don't Care.



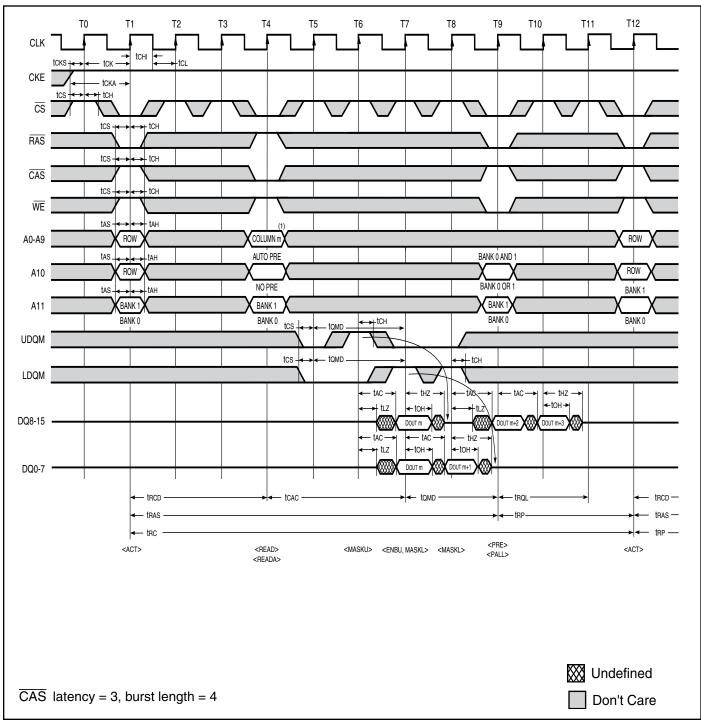
Write Cycle / Precharge Termination

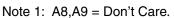






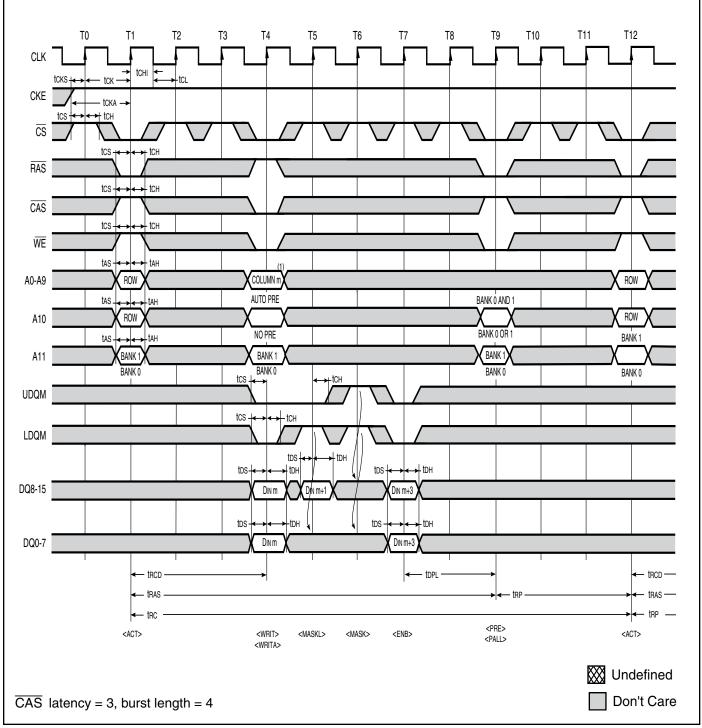
## Read Cycle / Byte Operation







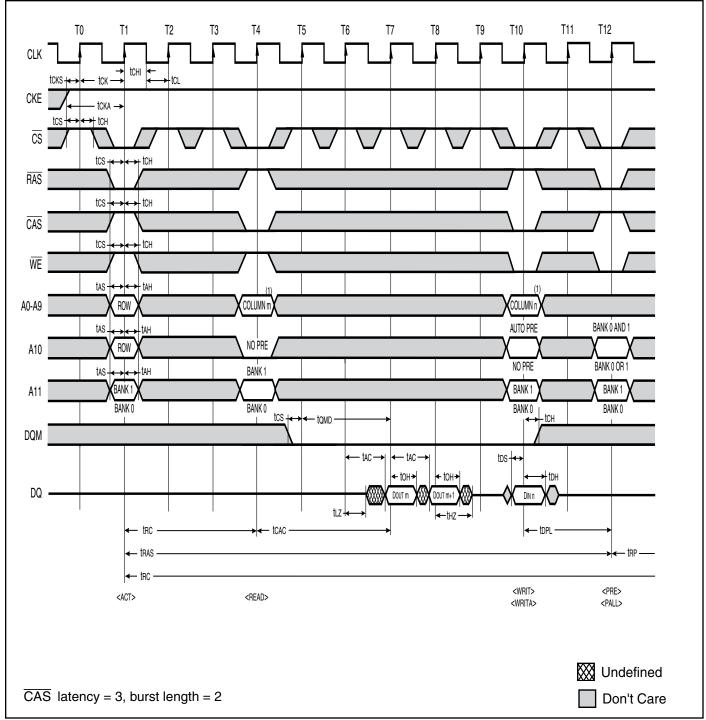
# Write Cycle / Byte Operation

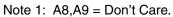


Note 1: A8,A9 = Don't Care.



# Read Cycle, Write Cycle / Burst Read, Single Write





# ORDERING INFORMATION

# Commercial Range: 0°C to 70°C

Frequency	Speed (ns)	Order Part No.	Package
200 MHz	5	IS42S16100H-5T	400-mil TSOP II
		IS42S16100H-5TL	400-mil TSOP II, Lead-free
		IS42S16100H-5BL	60-ball BGA, Lead-free
166 MHz	6	IS42S16100H-6T	400-mil TSOP II
		IS42S16100H-6TL	400-mil TSOP II, Lead-free
_		IS42S16100H-6BL	60-ball BGA, Lead-free
143MHz	7	IS42S16100H-7T	400-mil TSOP II
		IS42S16100H-7TL	400-mil TSOP II, Lead-free
		IS42S16100H-7BL	60-ball BGA, Lead-free

## Industrial Range: -40°C to +85°C

Frequency	Speed (ns)	Order Part No.	Package
166 MHz	6	IS42S16100H-6TLI	400-mil TSOP II, Lead-free
		IS42S16100H-6BLI	60-ball BGA, Lead-free
143MHz		IS42S16100H-7TLI	400-mil TSOP II, Lead-free
		IS42S16100H-7BLI	60-ball BGA, Lead-free

Please contact ISSI for leaded parts support.

#### Automotive Range: -40°C to +85°C

Frequency	Speed (ns)	Order Part No.	Package
166 MHz	6	IS45S16100H-6TLA1	400-mil TSOP II, Lead-free
		IS45S16100H-6BLAI	
143MHz	7	IS45S16100H-7TLA1	400-mil TSOP II, Lead-free
		IS45S16100H-7BLA1	60-ball BGA, Lead-free

#### Automotive Range: -40°C to +105°C

Frequency	Speed (ns)	Order Part No.	Package
143MHz	7	IS45S16100H-7TLA2	400-mil TSOP II, Lead-free
		IS45S16100H-7BLA2	60-ball BGA, Lead-free

# IS42S16100H, IS45S16100H



